

Energy-Efficient CMOS Optical Receiver for Short-Reach Data Center Application

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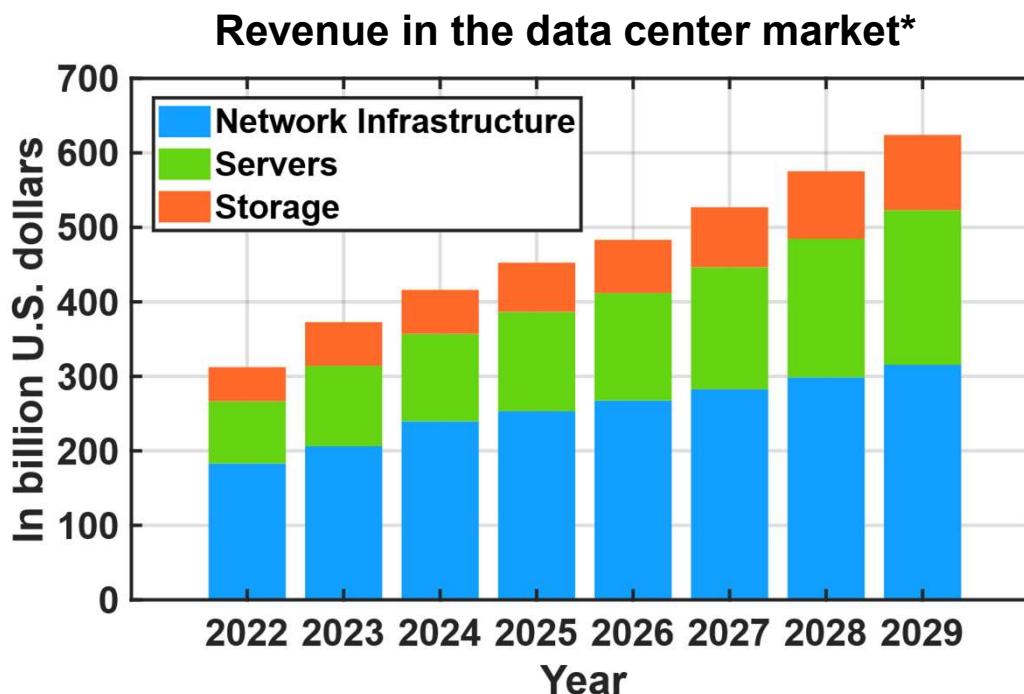
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Outline

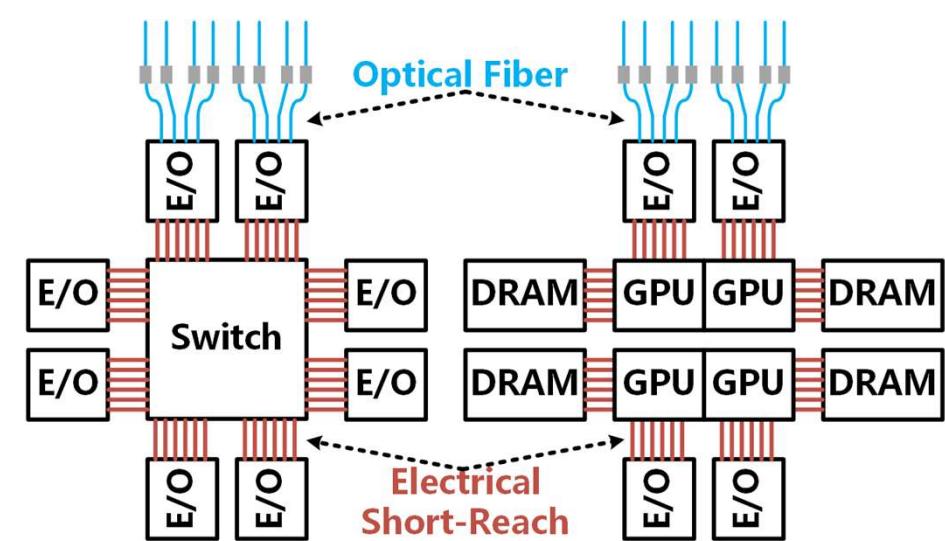
- › **Background**
- › **PAM-4 Optical Receiver Data Path**
- › **PAM-4 Optical Receiver Front End**
- › **Conclusion**

Research Background

- Data center networks keep scaling in BW and physical size
- Optical interconnects offer enhanced traffic capacity and reduced power consumption
- Further scaling of efficiency and density remains challenging due to limited integration in optical modules

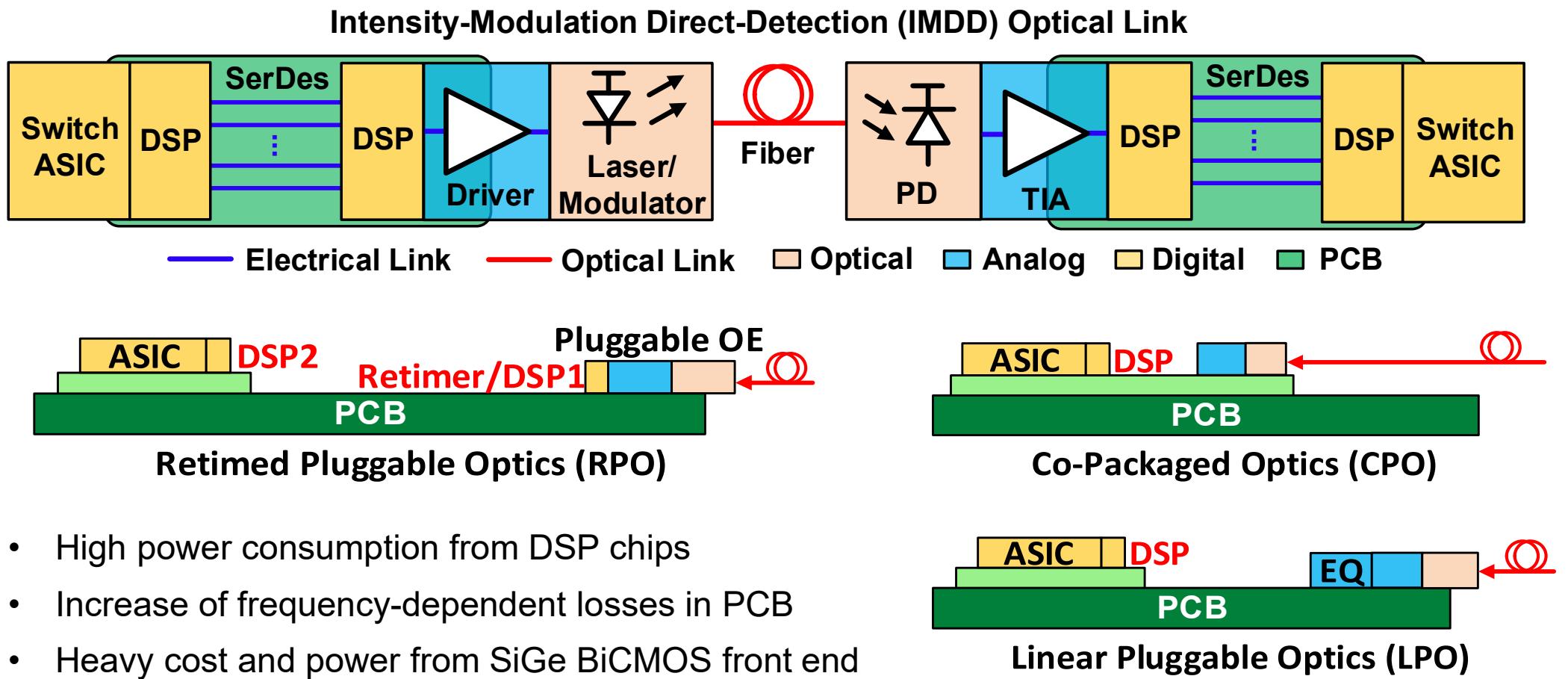


Network switch arrays with E/O interfaces



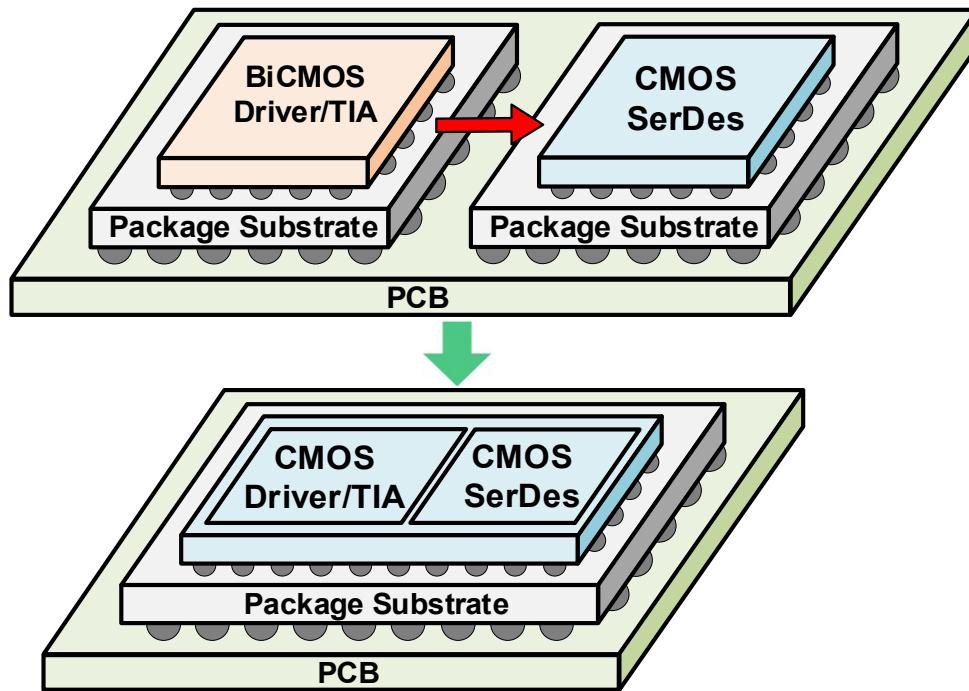
(*Revenue in the Data Center market for different segments Worldwide from 2018 to 2029 [Graph], Statista Market Insights, July 22, 2024. [Online]. Available: <https://www.statista.com/forecasts/1441973/revenue-data-center-market-for-different-segments-worldwide/>.)

Development Trend in Optical Interconnect



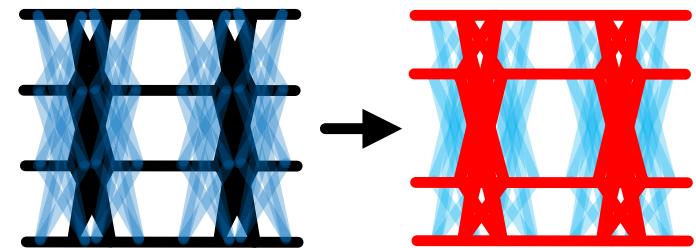
SerDes: Serializer/Deserializer; DSP: digital signal processor; ASIC: application-specific integrated circuit

Design Challenges

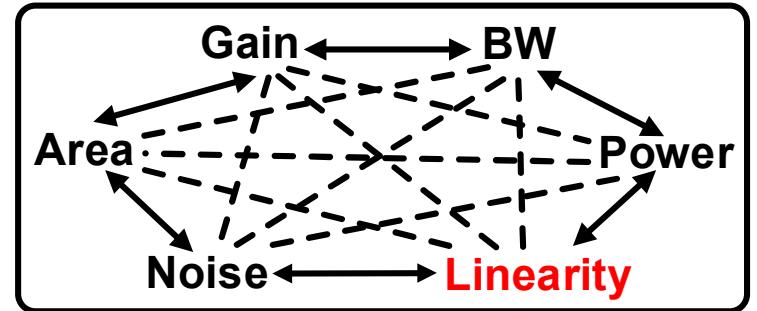


Integration of front-end transceivers in CMOS

- Lower f_T and intrinsic gain
- Worse noise performance
- Limited supply voltage



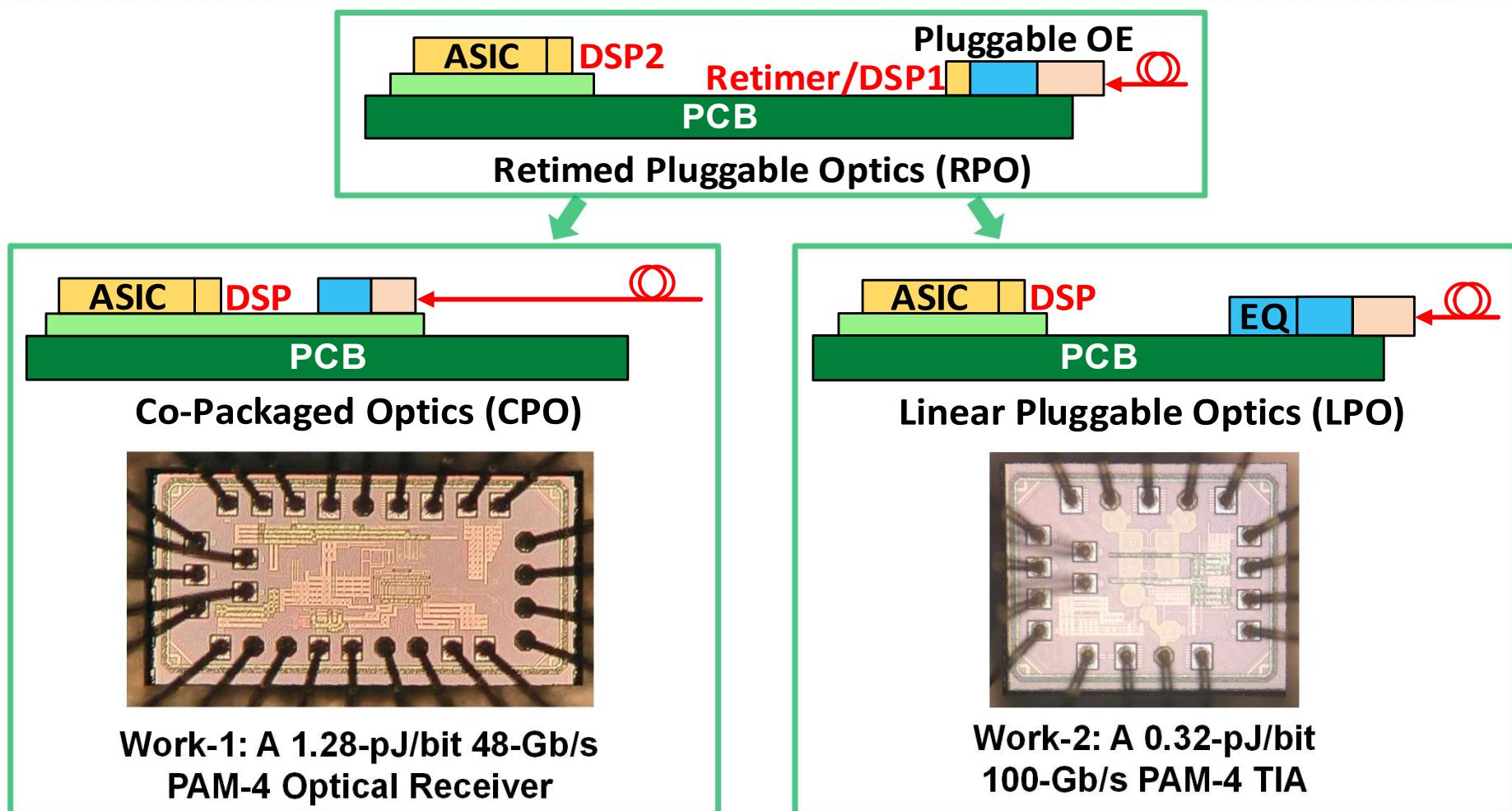
PAM-4 Design Tradeoffs



Adoption of four-level pulse amplitude modulation (PAM-4)

- ~9.5 dB worse signal-to-noise ratio (SNR)
- Higher linearity to preserve four symbols

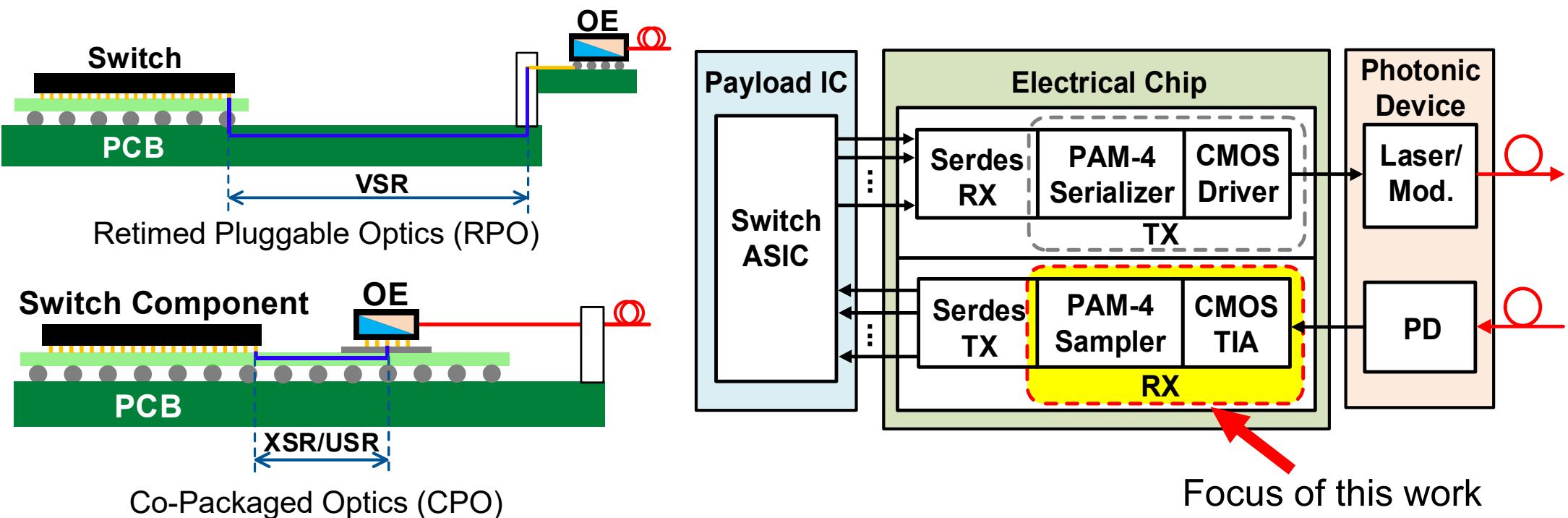
Research Scope



Outline

- › Background
- › **PAM-4 Optical Receiver Data Path**
 - System Architecture
 - Implementation
 - Measurement Result
- › PAM-4 Optical Receiver Front End
- › Conclusion

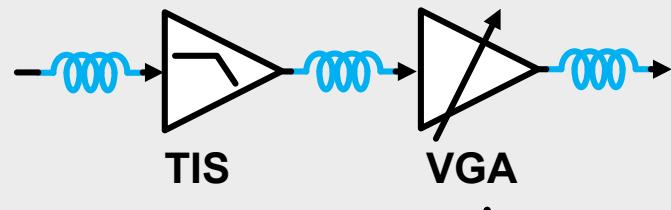
Data Center Optical Interconnect



- Integrating TIA and sampler (deserializer) reduces the overhead and electrical connections
- Low power consumption and low cost for 50-Gb/s link

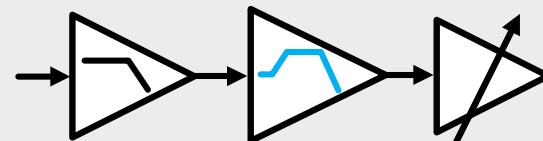
VSR: very short-reach; XSR: extra short-reach; USR: ultra short-reach

Design Challenges



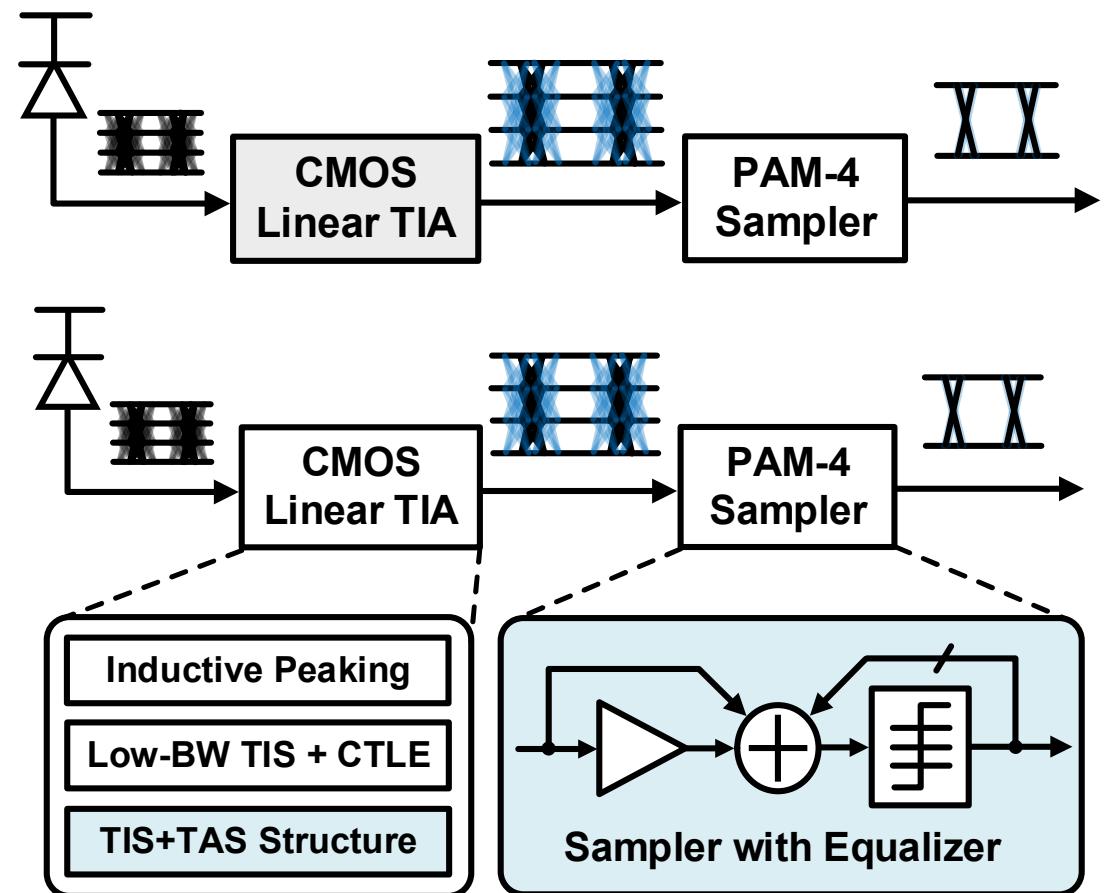
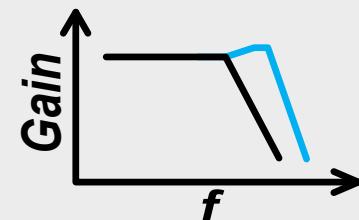
Inductive Peaking

- ✗ Large area
- ✗ Lack of tunability



Embedded CTLE

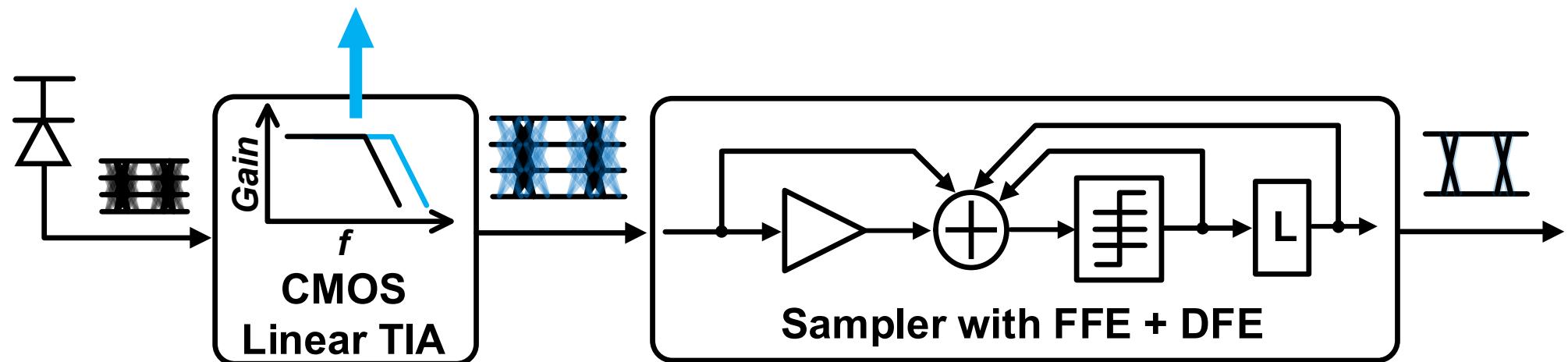
- ✗ In-band peaking
- ✗ Power hungry



TIS: transimpedance amplifier; VGA: variable gain amplifier; CTLE: continuous-time linear equalizer

RX Architectural Consideration

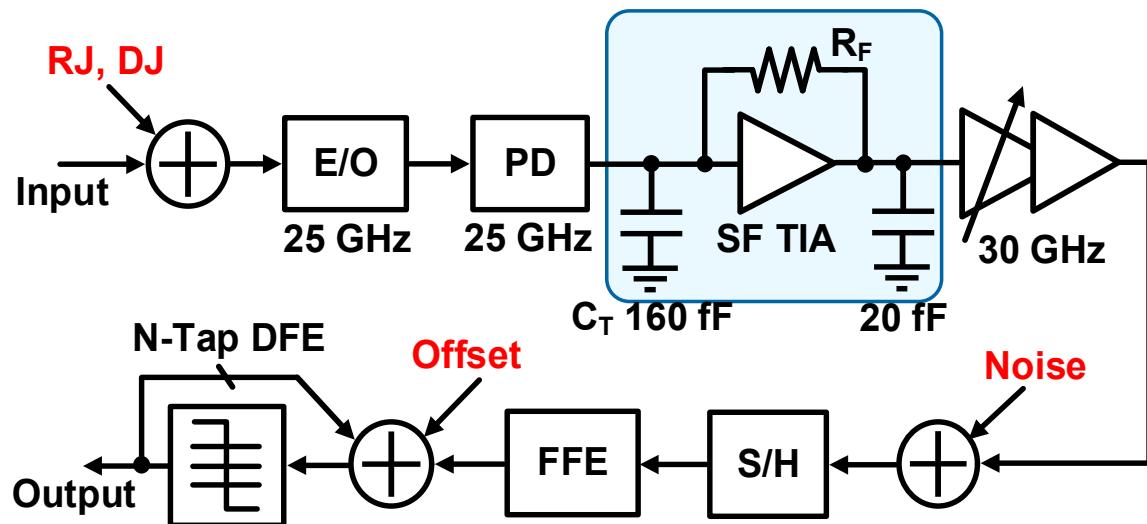
- CTLE is avoided to save power
- Passive inductors are avoided to save area
- Transadmittance-stage transimpedance-stage (TAS-TIS) topology is employed



- Equalizers are integrated at sampler to mitigate the residual ISI of TIA

ISI: intersymbol interference; FFE: feedforward equalizer; DFE: decision feedback equalizer

RX Architectural Consideration



$$BW_{3dB} = \frac{\sqrt{2A_0(A_0 + 1)}}{2\pi R_F C_T} \approx \frac{\sqrt{2A_0}}{2\pi R_F C_T}$$

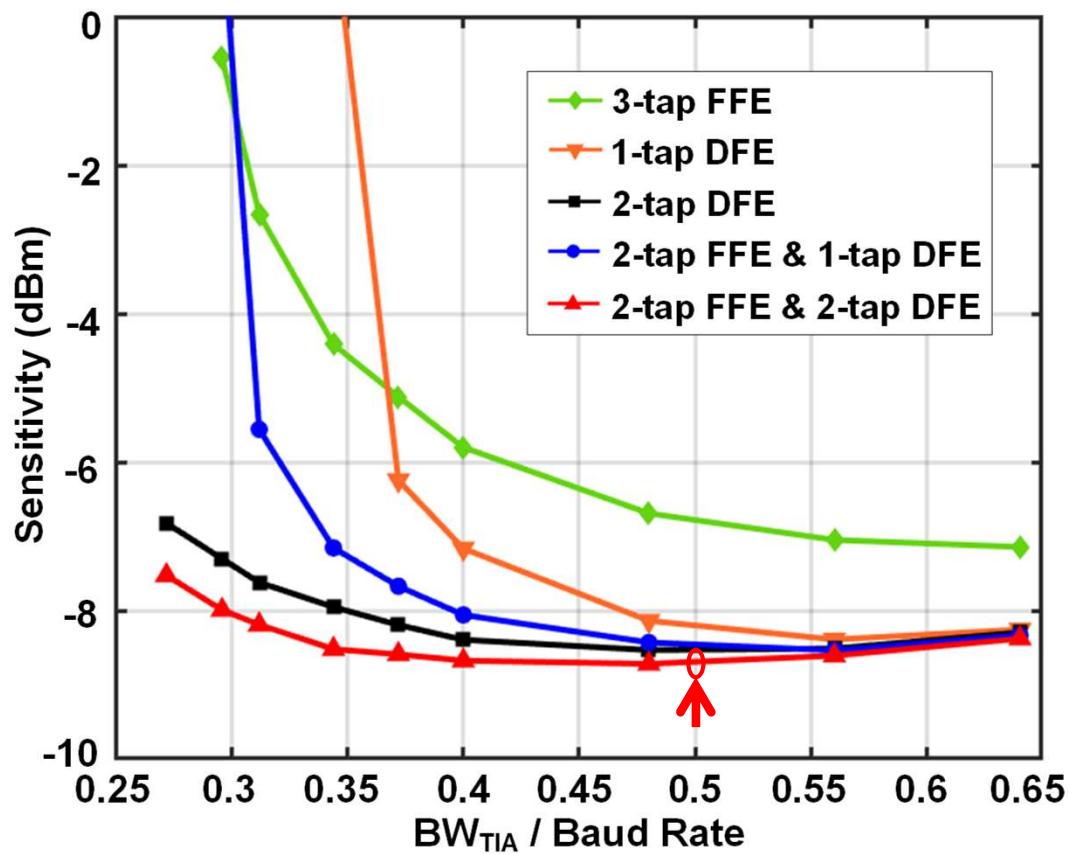
$$R_F = \frac{(A_0 + 1)\omega_A}{C_T BW_{3dB}^2} \approx \frac{GBW_A}{2\pi C_T BW_{3d}^2}$$

$$\overline{i_n^2} = 4kT \frac{2\pi C_T}{f_T} BW_{3dB}^3 \times \left(I_1 \times \frac{f_T}{GBW_A} + \frac{I_2^3}{3} \times 2\gamma \right)$$

- ORX link model to evaluate post-TIA equalization
- TIA model with a second-order flat response

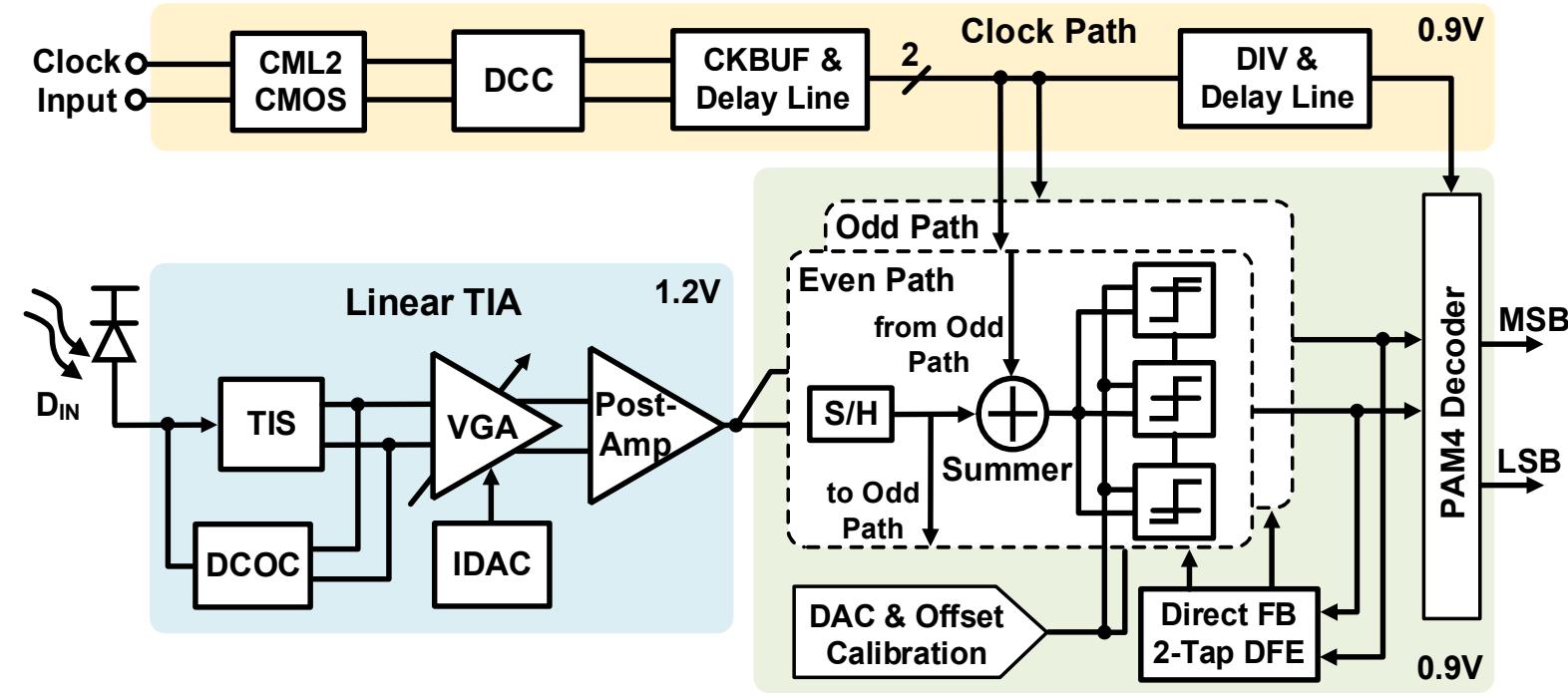
RJ: random jitter; DJ: duty cycle error

RX Architectural Consideration



- $BW_{TIA} < 0.45x$ baud rate, sensitivity is limited by ISI
- $BW_{TIA} > 0.45x$ baud rate, sensitivity is limited by noise
- A combination of a 2-tap FFE and a 2-tap DFE delivers the best overall sensitivity
- Optical receiver (ORX) is designed with a BW_{TIA} of $\sim 0.5x$ baud rate, followed by a 2-tap FFE and a 2-tap DFE

Proposed Architecture



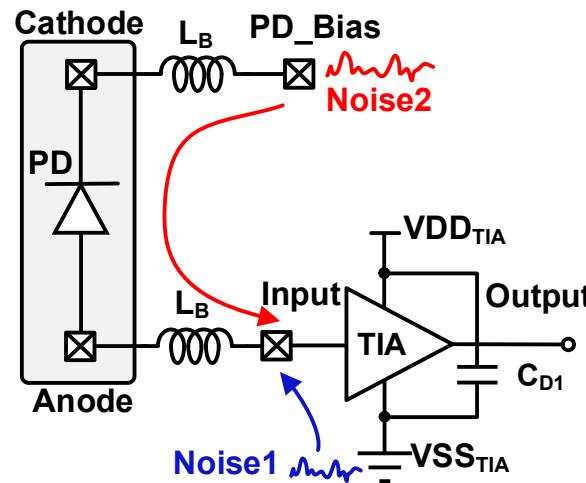
- **Linear TIA**
 - >73 dBQ maximum gain
 - >20 dB dynamic range
 - Compact and energy-efficient
- **PAM-4 sampler**
 - Half-rate structure
 - 2-tap FFE + 2-tap DFE
- **Clock path**
 - External differential clock
 - Voltage-controlled delay line
 - Divider (DIV)

DCOC: dc offset cancellation; DCC: duty cycle correction; MSB: most significant bit; LSB: least significant bit

Outline

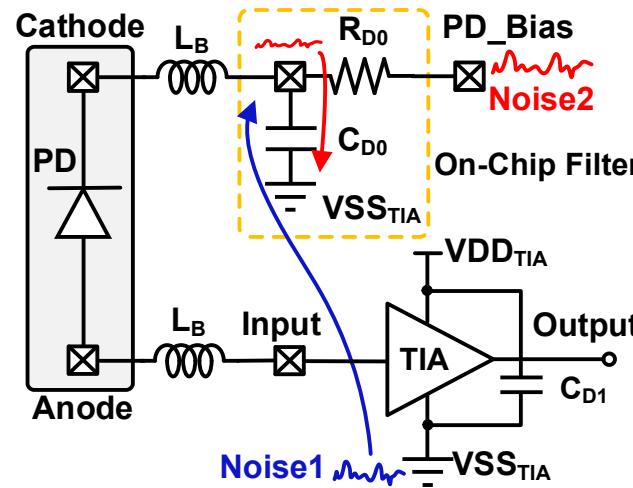
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PD Interface and TIS



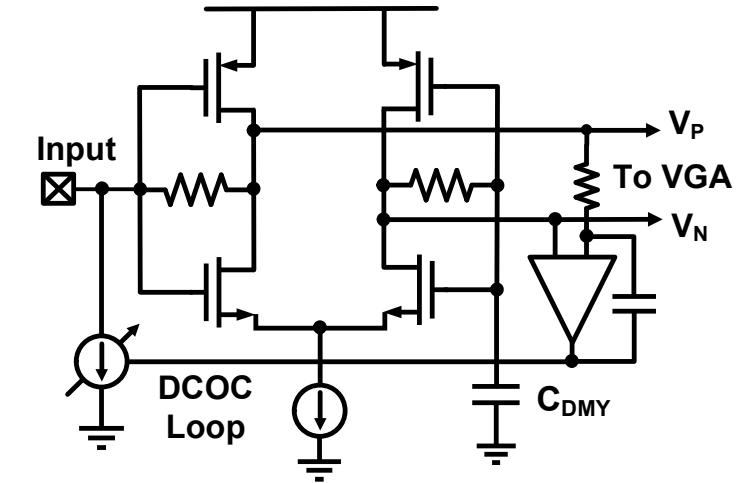
Direct connection scheme

- ✓ Simple and save pads
- ✗ Noise at VSS_{TIA} and PD bias affects the single-ended input signal



On-chip connection scheme

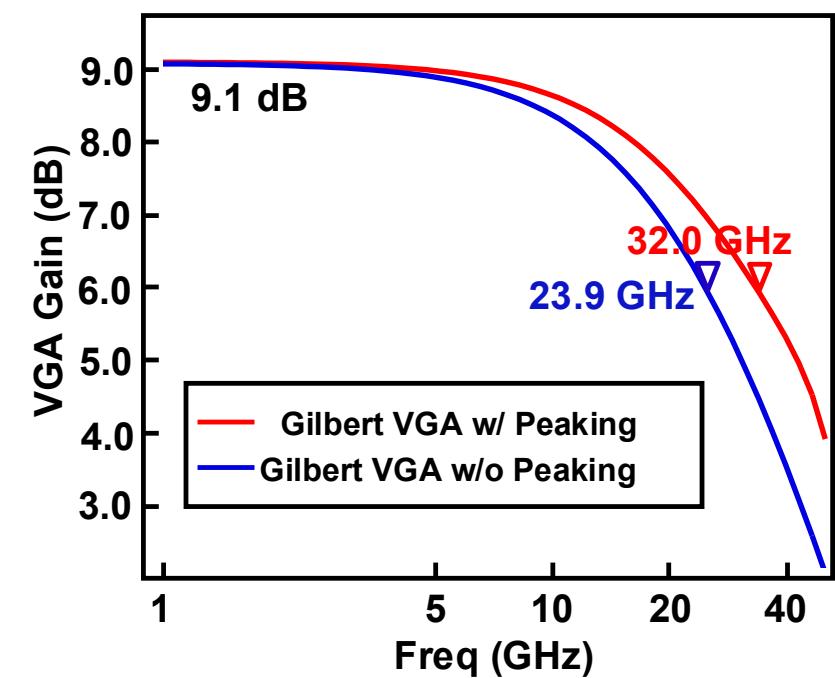
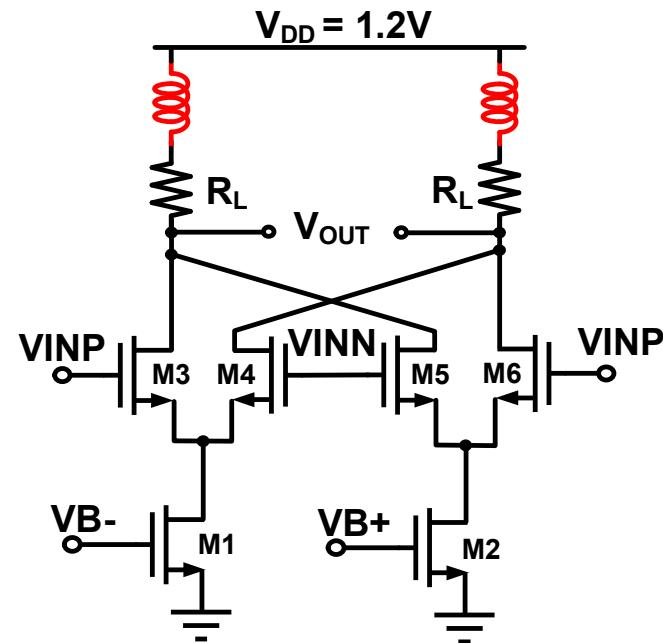
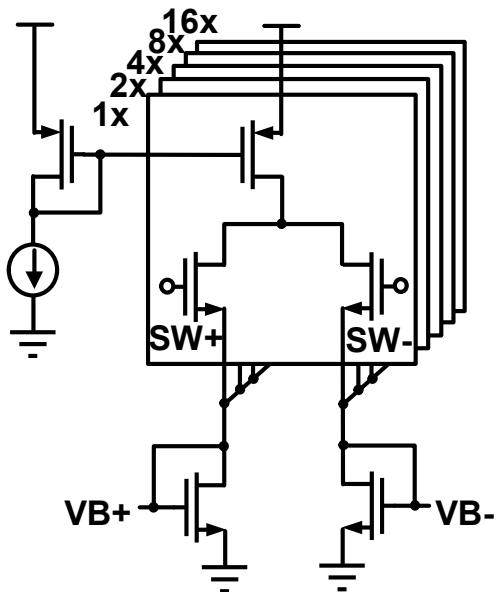
- ✓ Enhanced ground noise rejection by ac-coupled VSS_{TIA} and PD cathode
- ✓ R_{D0} and C_{D0} provide on-chip filtering for noise2



Schematic of TIS with DCOC

- Pseudo-differential push-pull TIS provides single-to-differential conversion
- Current tail for better supply noise rejection

Gilbert-Cell-Based VGA



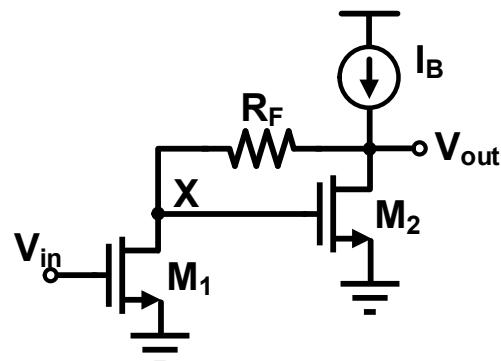
- 5-bit current DAC for G_m control
- Gain = $G_m \cdot R_L$, fixed load impedance: R_L
- Shunt peaking required to expand BW

- Two 580-pH inductors required to expand the BW to 32 GHz

VGA Employing TAS-TIS Topology

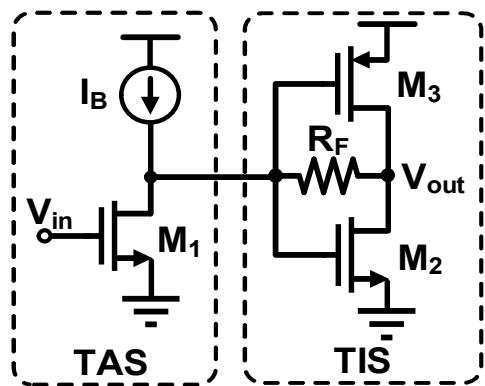
Cherry-Hooper Amp

- $Z_X \approx \frac{1}{g_{m2}}$
- $Z_{out} \approx \frac{1}{g_{m2}}$

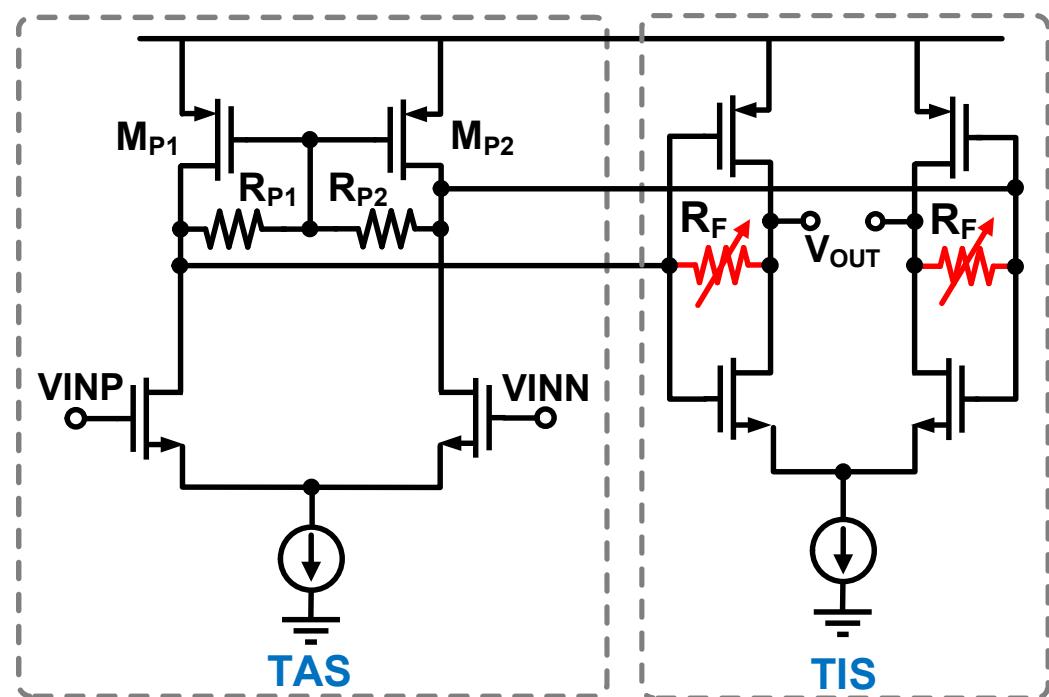


TAS-TIS topology

- Modified Cherry-Hooper Amplifier
- Split into two stages: TAS and TIS

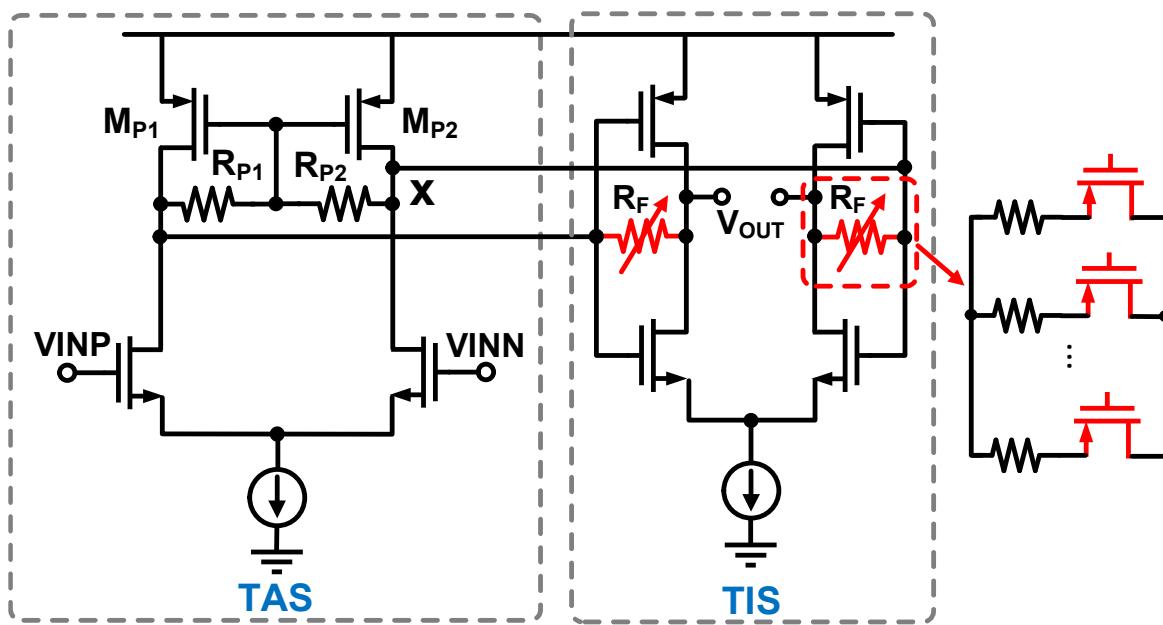


VGA employing a TAS-TIS topology

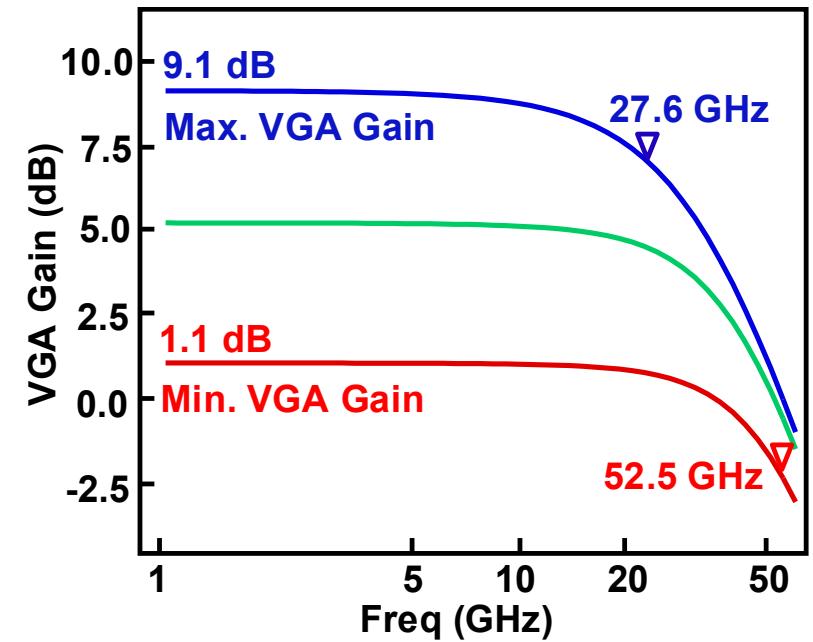


TAS: transadmittance stage TIS: transimpedance stage

VGA Employing TAS-TIS Topology

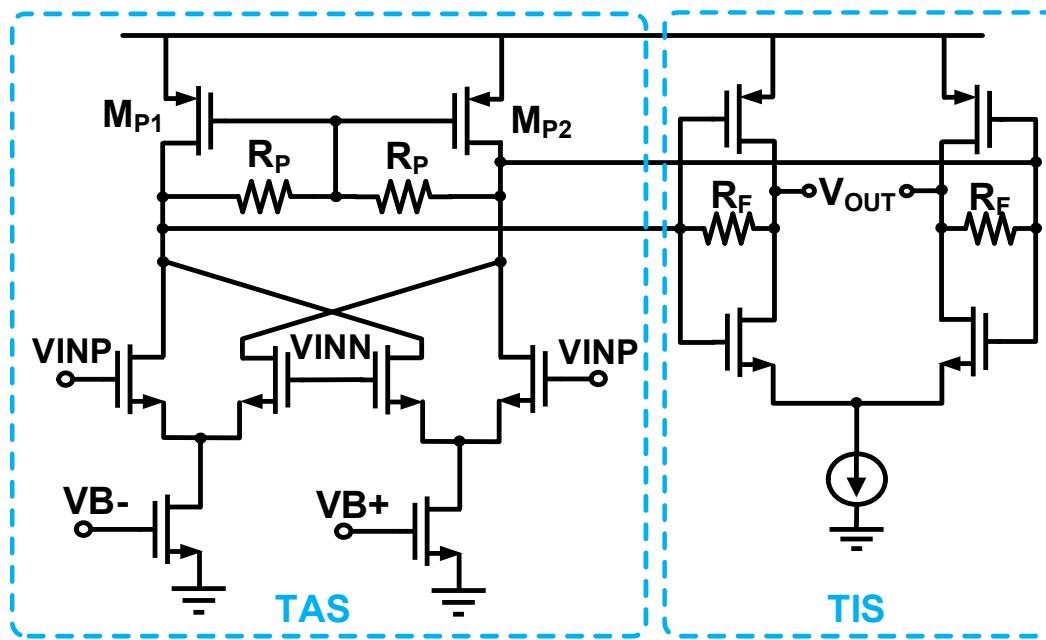


- Gain = $Gm_{TAS} \times R_F$
- Load impedance of TAS: R_F / A_{TIS} , higher BW
- Output impedance: $1/Gm_{TIS}$, larger driving capacity
- Variable R_F causes BW variations over gain variations
- Switches for R_F control bring extra parasitics

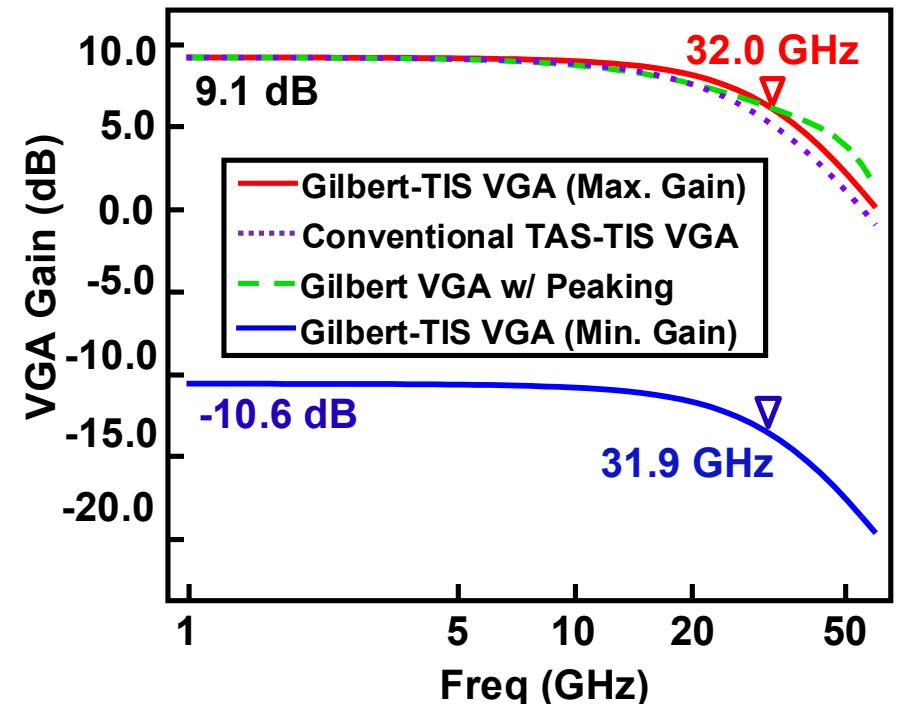


- 3-bit TAS-TIS VGA
- 8-dB gain tuning range
- ~25-GHz BW variation

Proposed Gilbert-TIS VGA

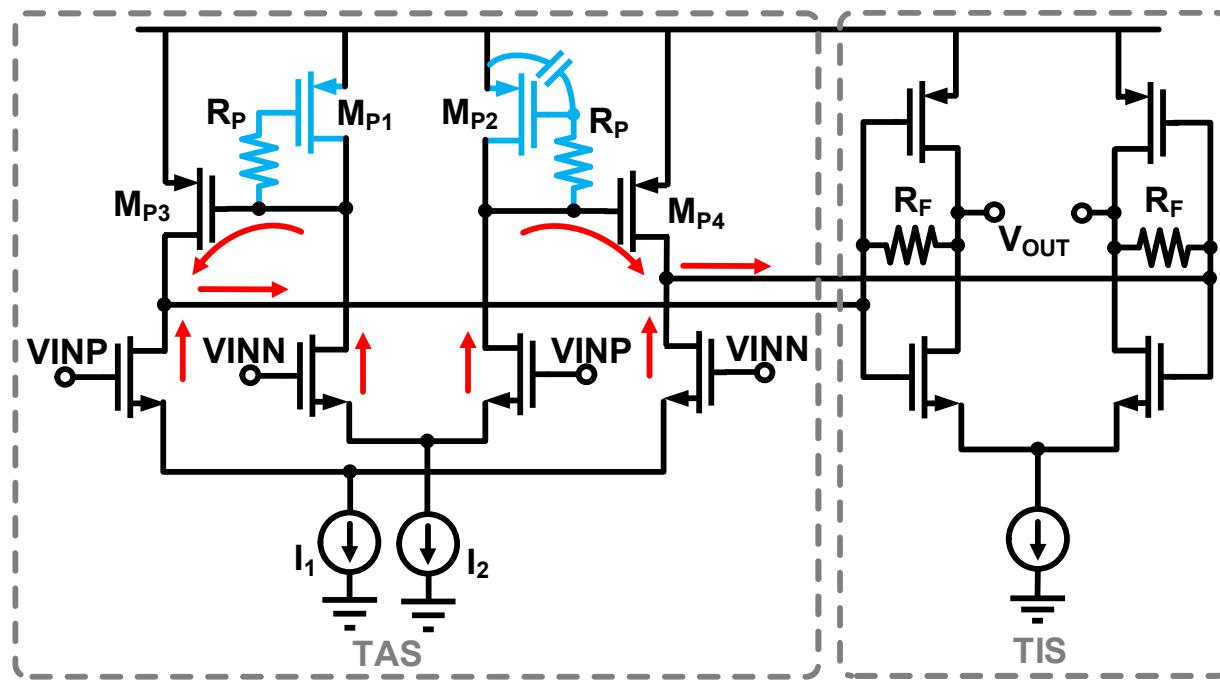


- Load impedance of TAS: R_F/A_{TIS} , higher BW
- Output impedance: $1/Gm_{TIS}$, larger driving capacity
- Fixed R_F mains a constant BW over gain variations
- CML-based TAS to get fully differential signal

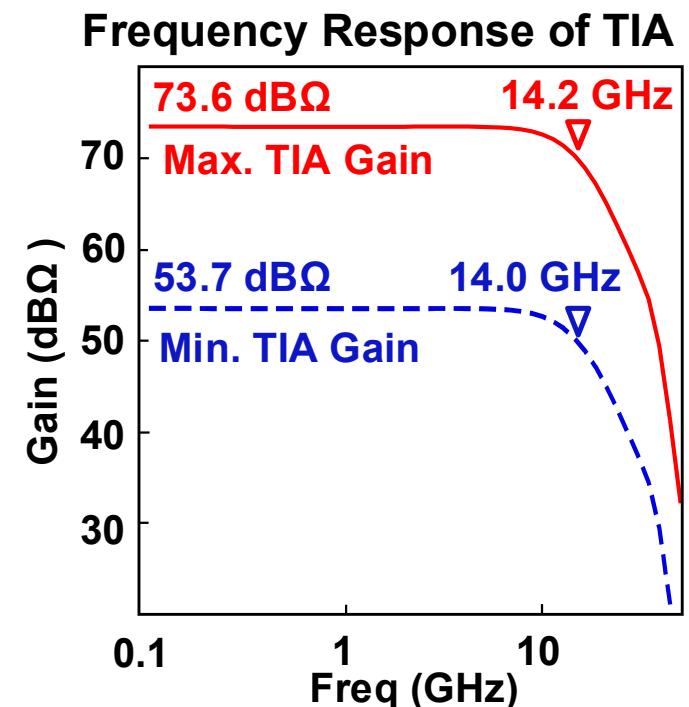


- High gain-BW product
- <0.2-GHz BW variation

Post-Amp Design and TIA Frequency Response

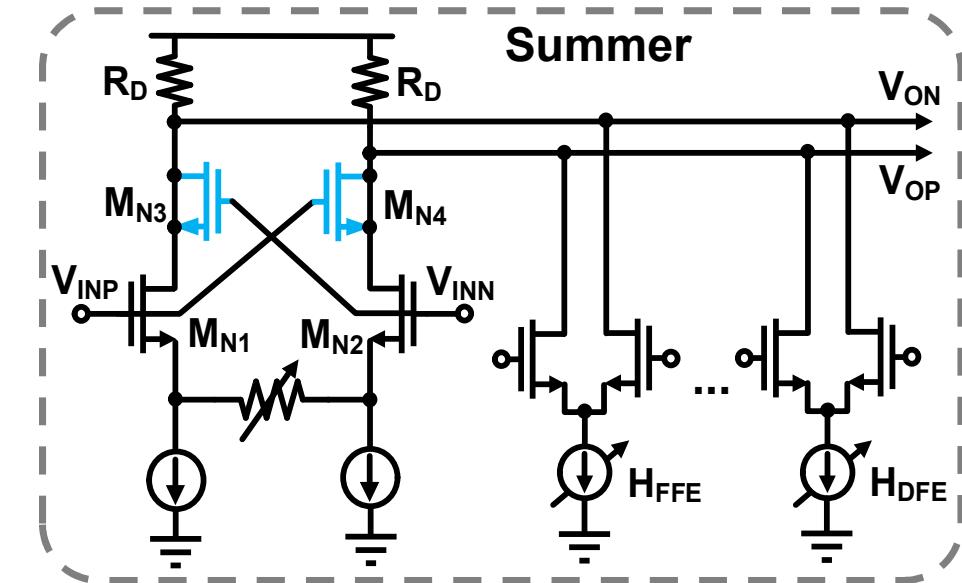
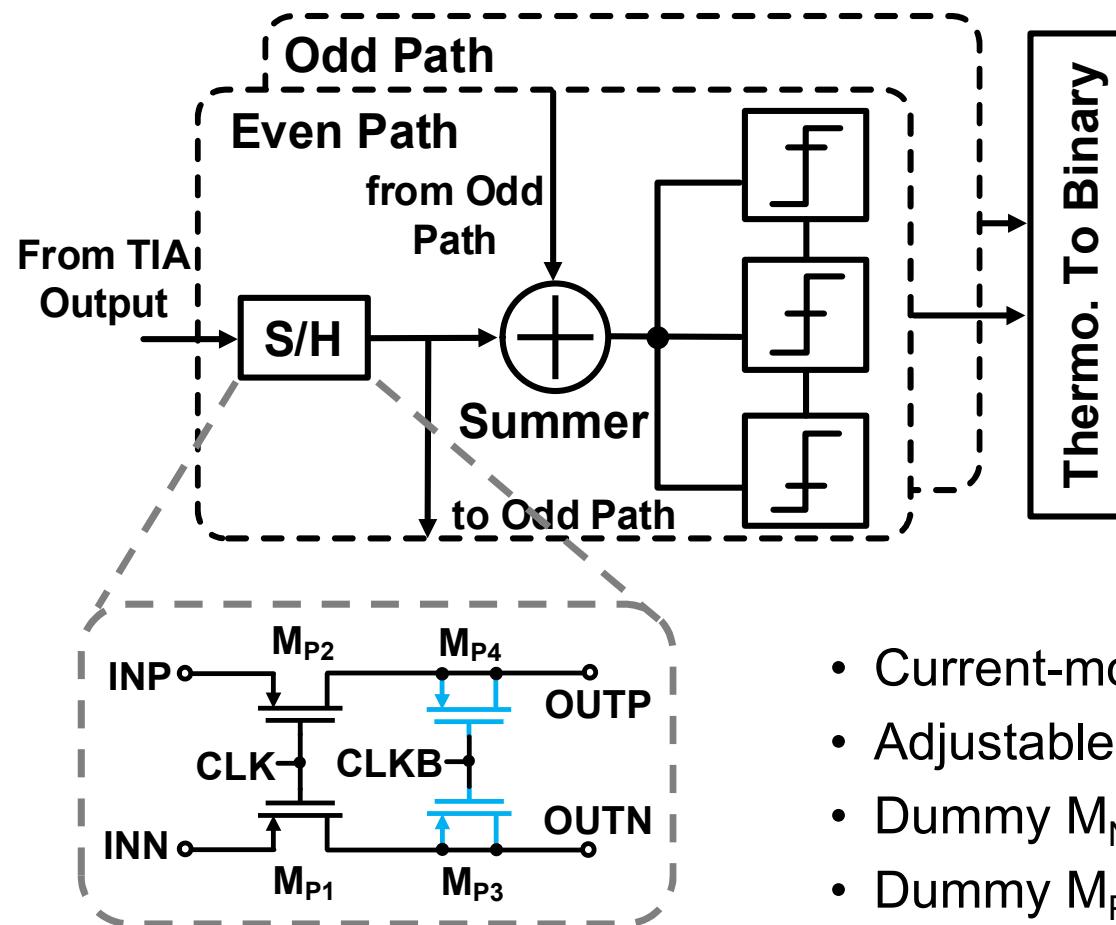


- TAS-TIS topology
- Two differential pairs to achieve high Gm_{TAS}
- R_P, M_{P1}, M_{P2} form active inductors to expand BW



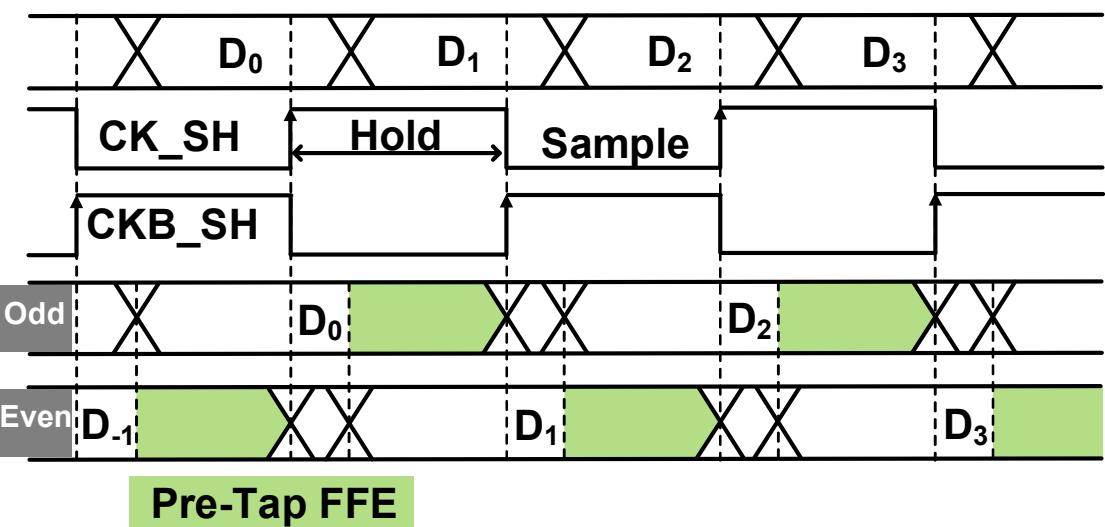
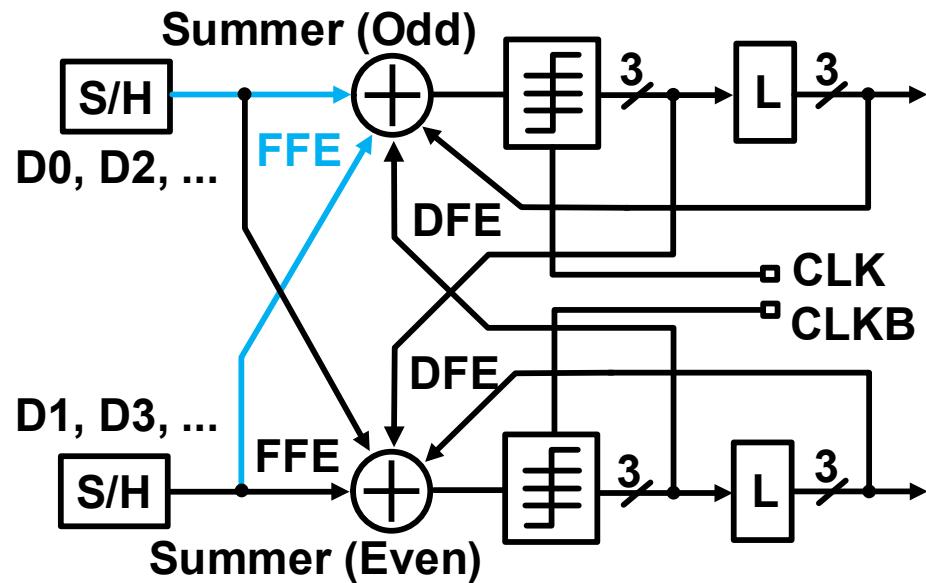
- TIA achieves 73.6-dB Ω max. gain with 14.2-GHz BW
- < 0.3 GHz BW variation

Sampler with Integrated Equalizer



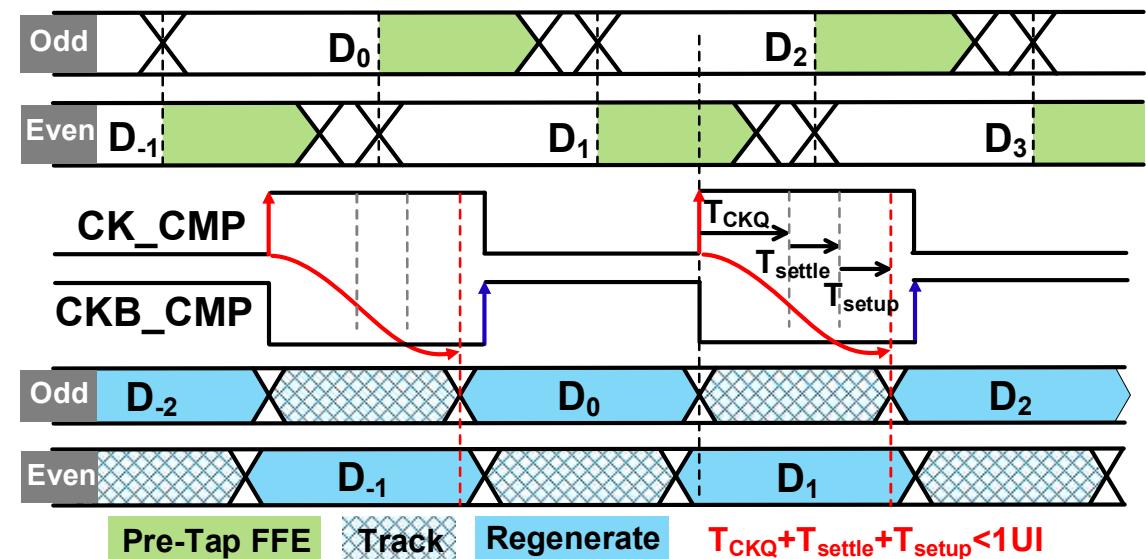
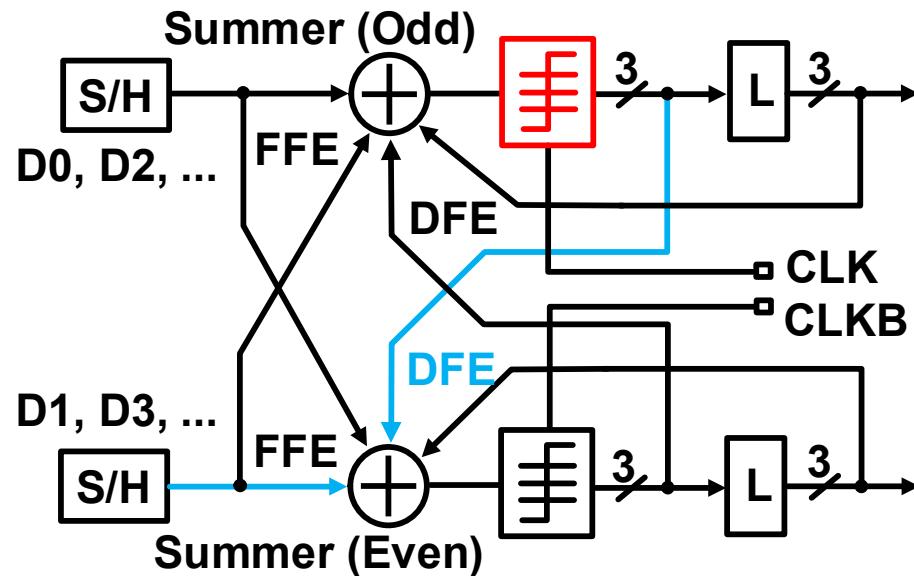
- Current-mode summer with resistive load
- Adjustable degeneration resistor to improve linearity
- Dummy M_{N3}/M_{N4} to reduce feedback from V_{OP}/V_{ON}
- Dummy M_{P3}/M_{P4} to mitigate clock through from M_{P1}/M_{P2}

FFE and Summer Timing Diagram



- Data is sampled and held for 1 UI by S/H circuits using CK_SH and CKB_SH alternatively
- Data in the even path experiences an 1-UI delay relative to the odd path
- 0.5-UI precursor of D_1 is cancelled by subtracting D_2 from D_1

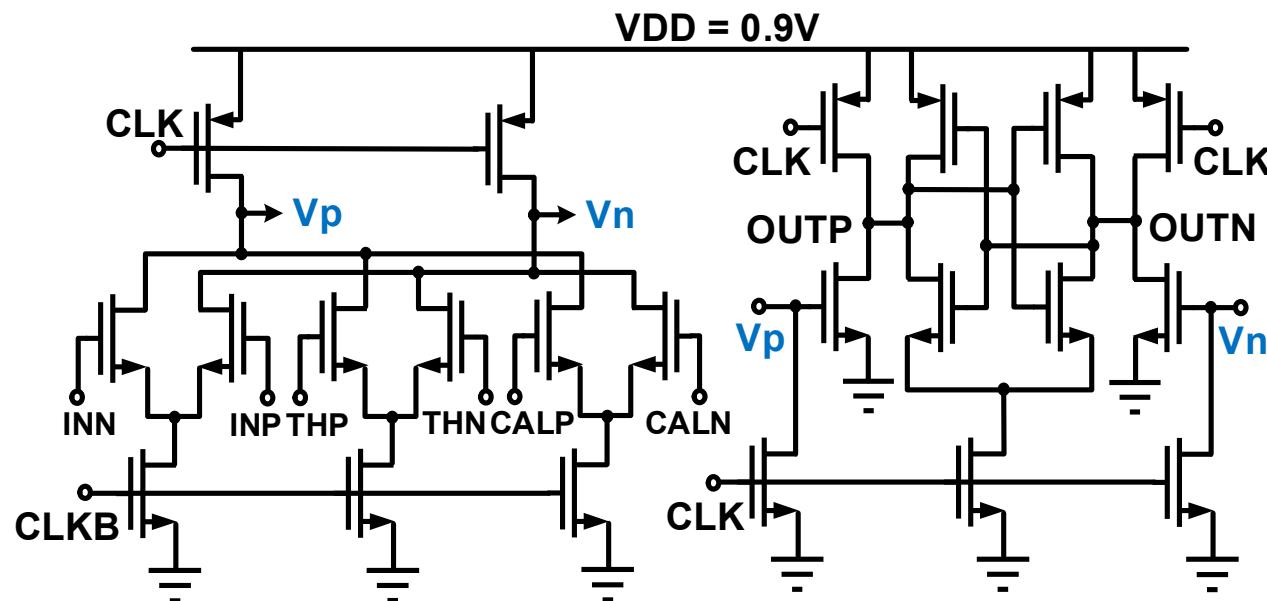
DFE and Summer Timing Diagram



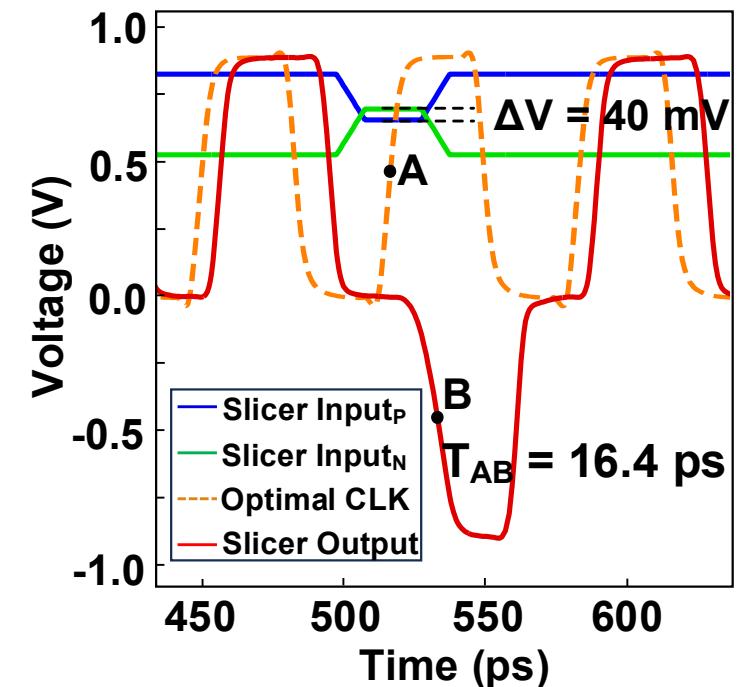
- Before D_1 is sliced by the rising edge of CK_CMP, D_0 must be regenerated and subtracted from D_1
- Stringent timing constrain to close decision feedback loop for the first tap
- $1\text{-UI} < 42\text{ps}$ for 48-Gb/s PAM-4 operation
- The delay performance of slicers is critical: **reduce T_{ckq}**

UI: unit interval

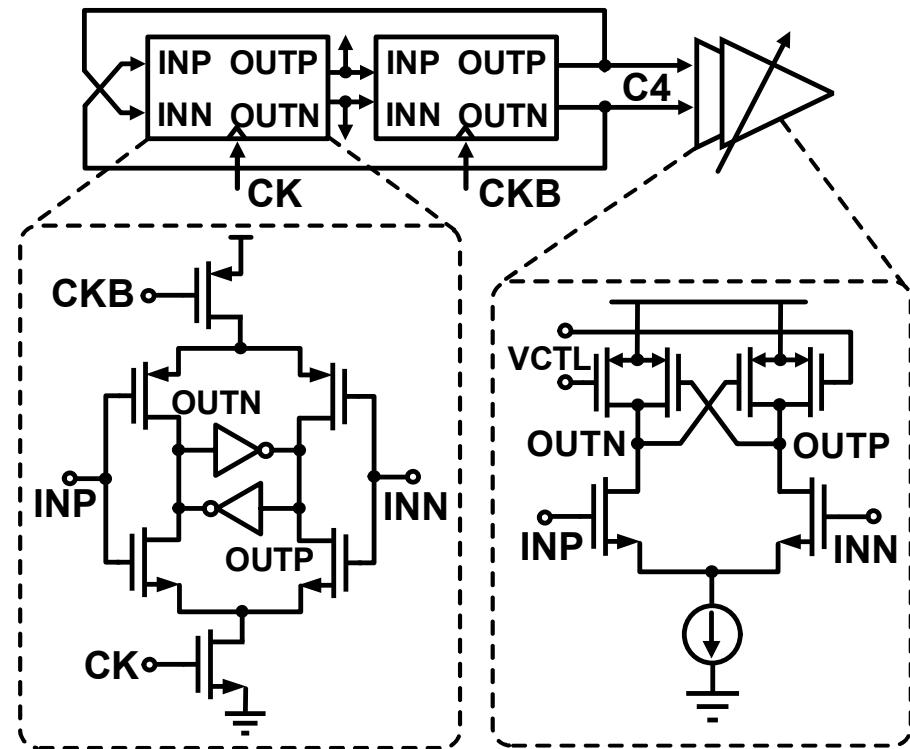
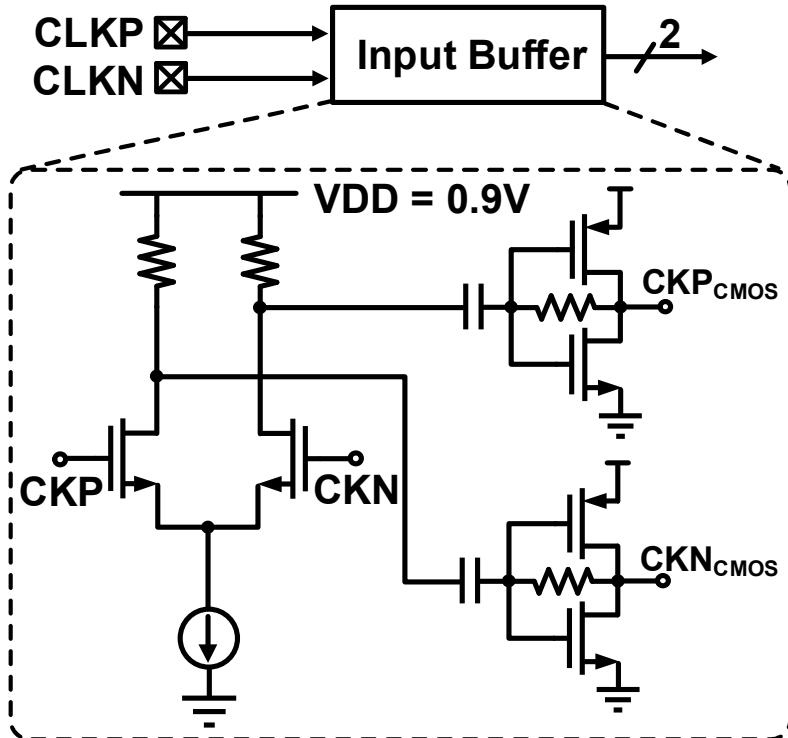
Track-and-Regenerate Slicer



- Track-and-regenerate slicer
- $CLK=0$, $CLKB=1$, input tracked by V_p and V_n , latch is charged to V_{DD}
- $CLK=1$, $CLKB=0$, V_p and V_n discharged to V_{SS} , latch regenerates signal
- Optimized clock-to-Q delay, $< 17ps$

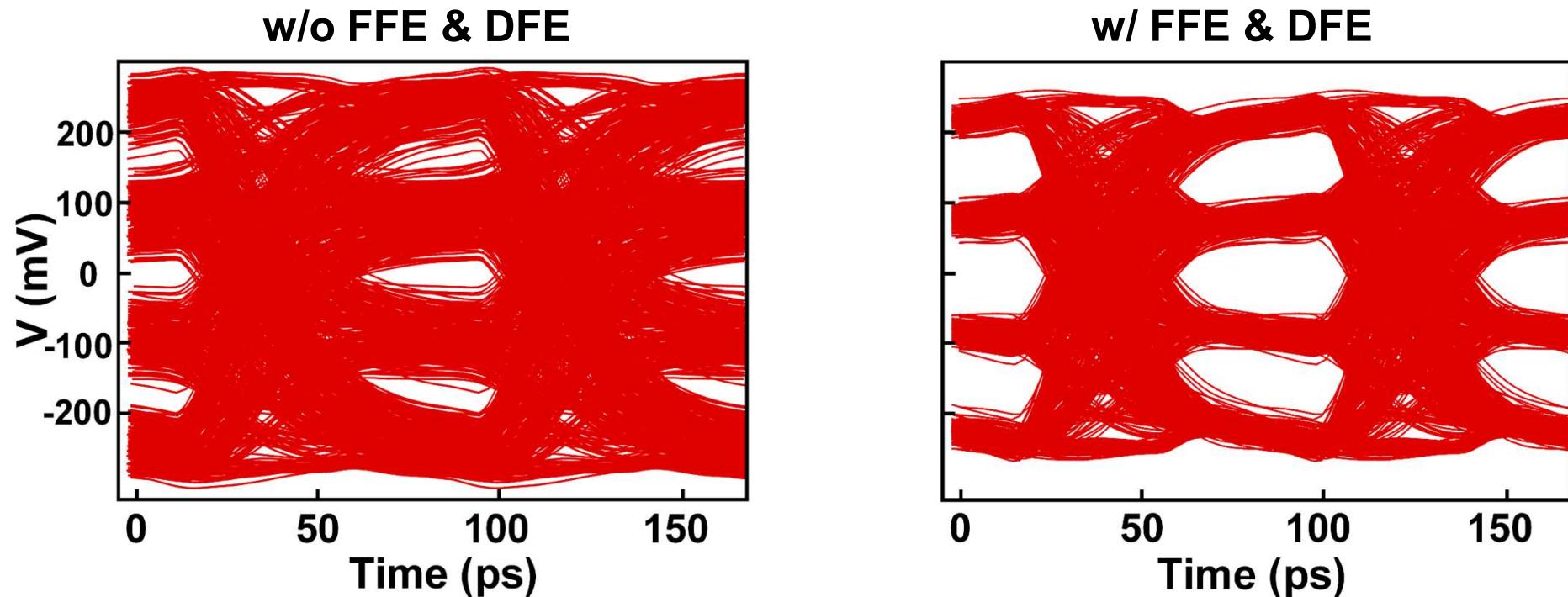


Clock Path



- CML to CMOS clock buffer amplifies sinusoidal clock signals to rail-to-rail
- C²MOS frequency divider is used to provide clock signals for PAM-4 decoder
- Delay line controlled by a 6-bit R2R ladder is used to accommodate delay variations

Simulated Eye Diagram at Summer Output

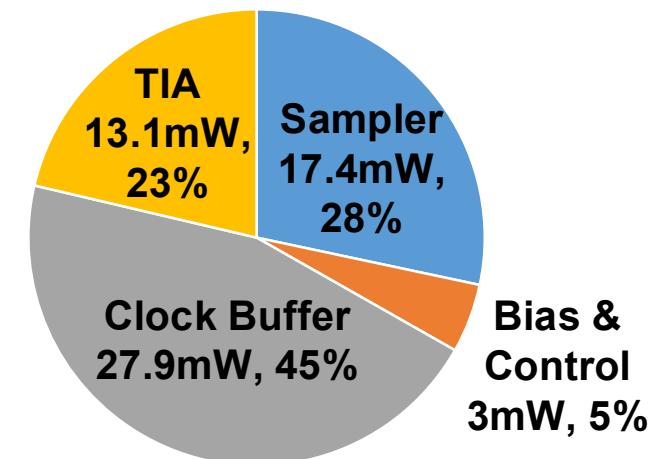
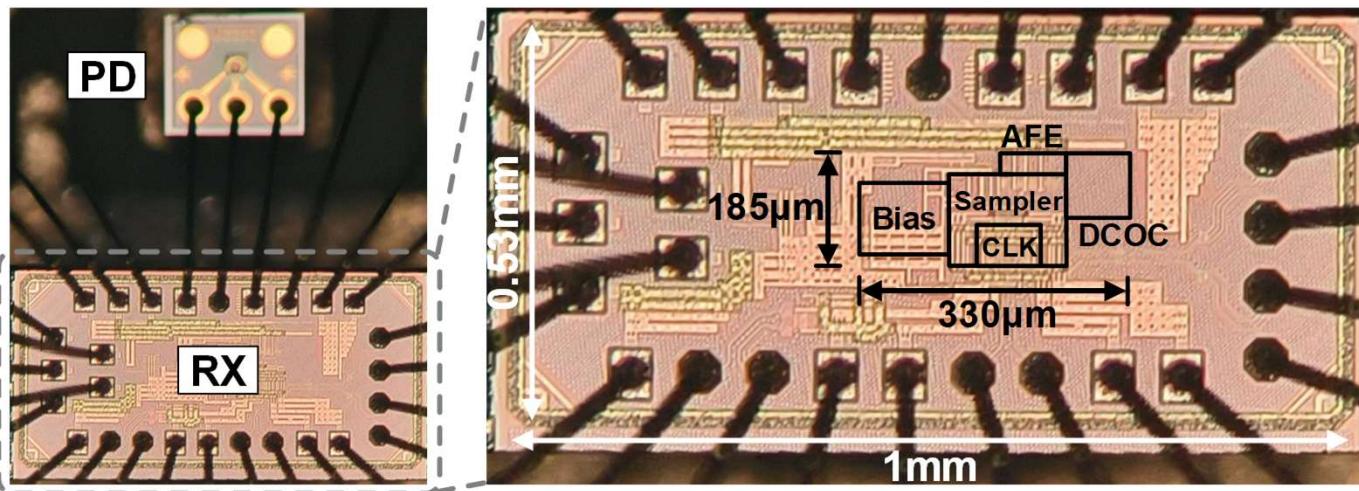


- 48-Gb/s PAM-4 input with 220-uA amplitude, 70-fF PD, 1.5-ps RJ
- Eye diagrams of half-rate 24-Gb/s PAM-4 at summer output before decoding
- Coefficients of FFE, first-tap DFE, second-tap DFE: 0.07, 0.08, 0.01

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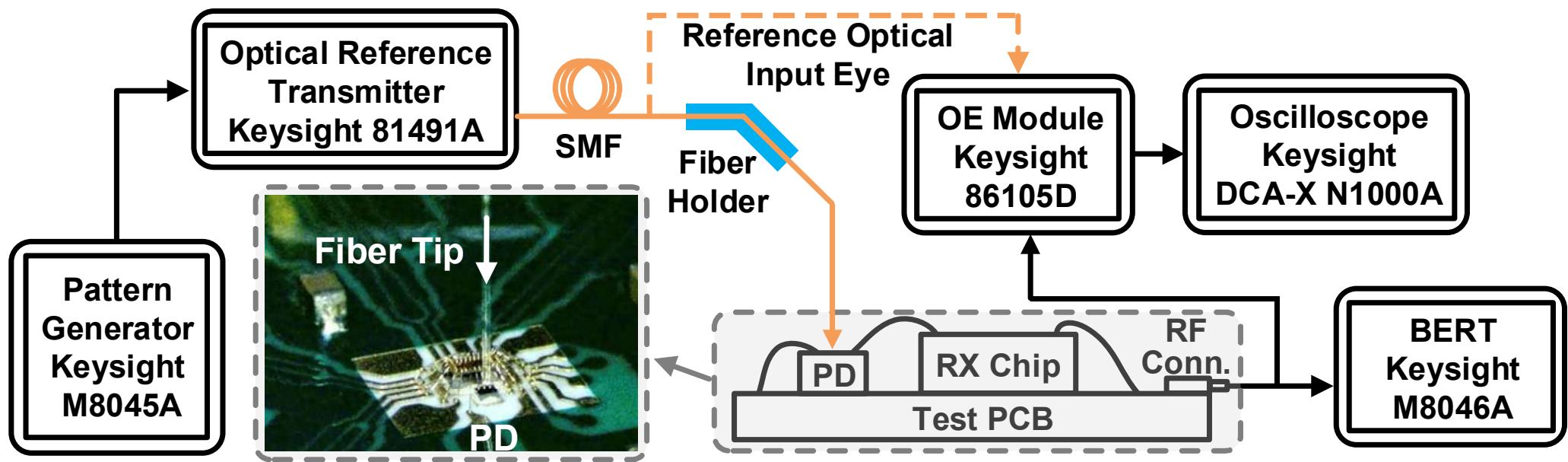
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Die Photo and Power Breakdown



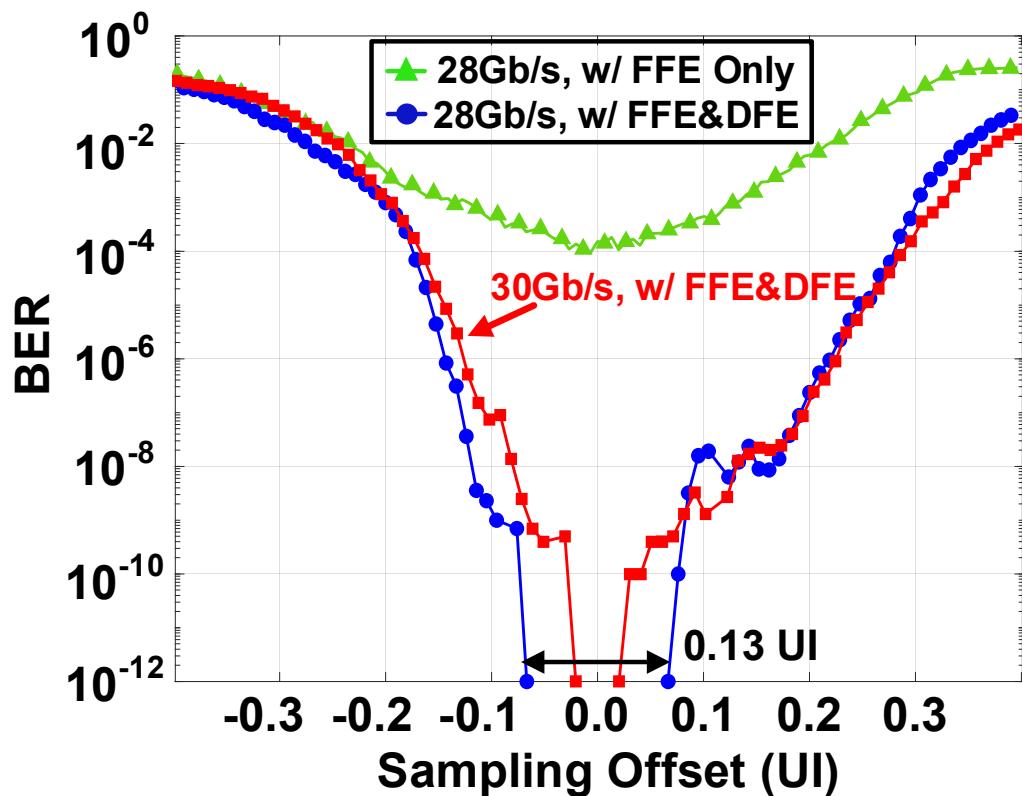
- Fabricated in a 28-nm bulk CMOS
- ~0.06 mm² core area for ORX
- Wire-bonded to a 27-GHz PD with 0.75-A/W responsivity
- 61.4 mW at 48-Gb/s in total, TIA contributing 13.1 mW

Measurement Setup



- 1308-nm light source is coupled to PD through a single-mode fiber
- Optical power level is adjusted by an internal optical attenuator
- Deserialized MSB and LSB are sent to off-chip BER testing

NRZ BER Bathtub Curves

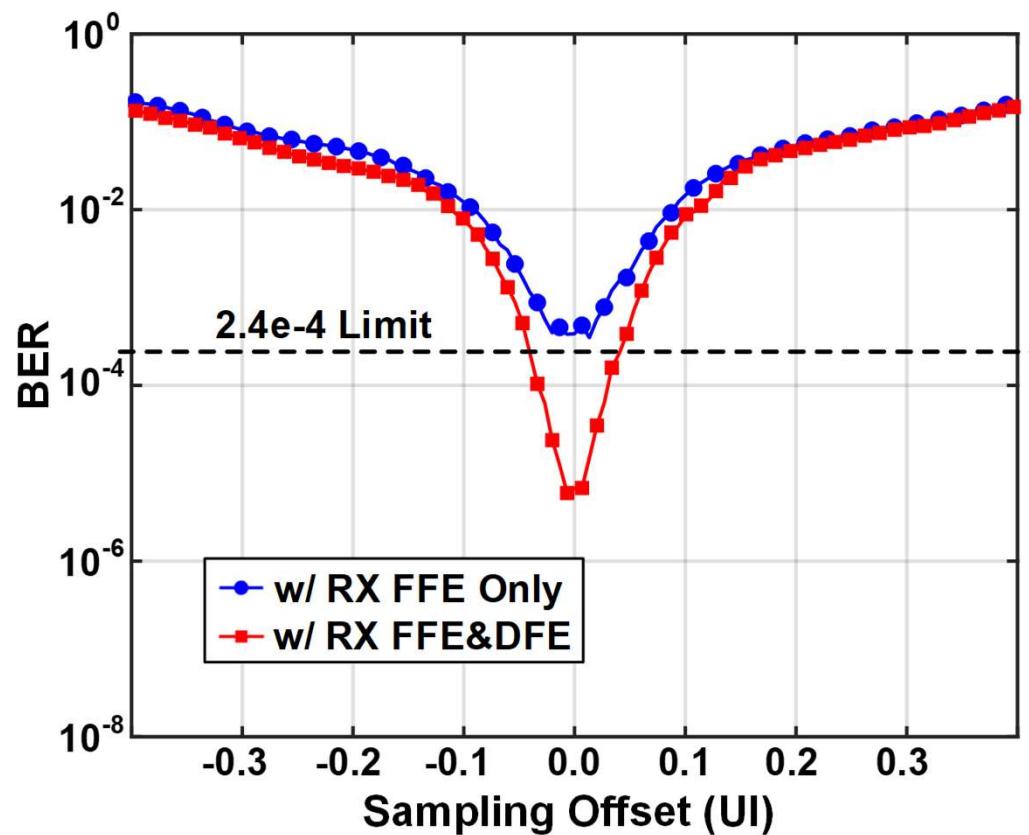


NRZ input signal

- All data slicers are enabled without PAM-4 threshold voltages
- 28-Gb/s NRZ input with -8.0-dBm input OMA
- 30-Gb/s NRZ input with -7.7-dBm input OMA
- $1e-12$ BER at 30-Gb/s validate slicer design and DFE operation

BER: bit error rate; OMA: optical modulation amplitude

PAM-4 BER Bathtub Curves

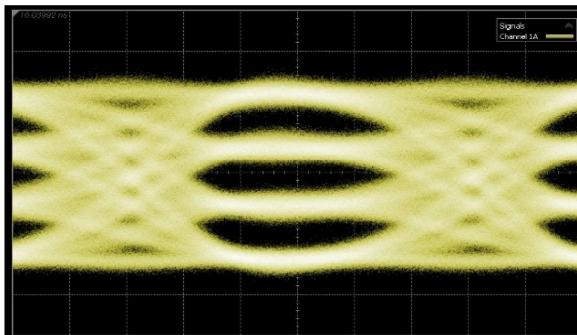


PAM-4 input signal

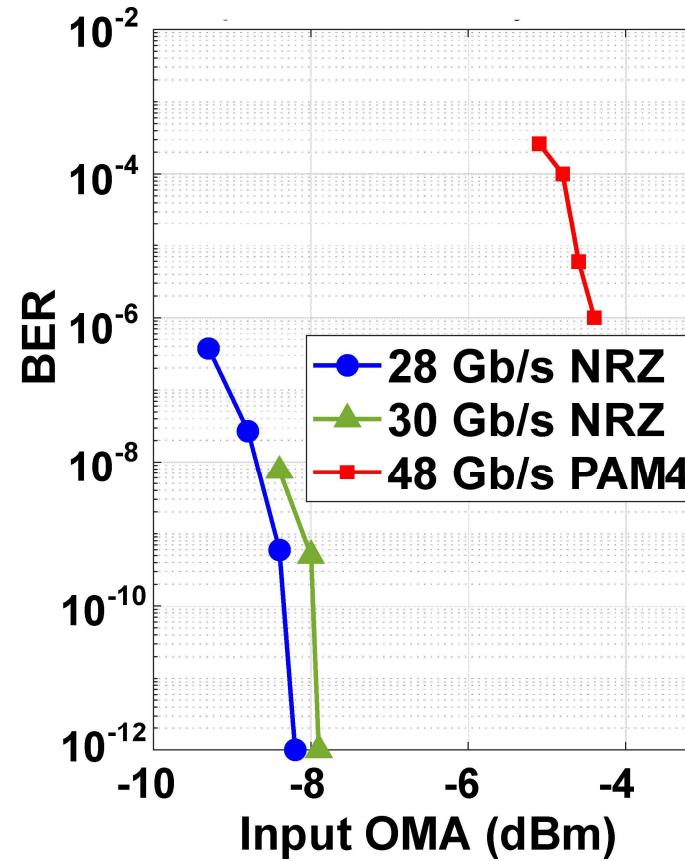
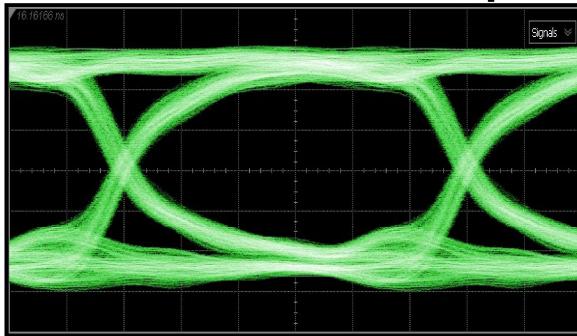
- 48-Gb/s PAM4 with -4.6-dBm input OMA
- Only enabling FFE, BER is higher than pre-FEC limit
- After enabling both FFE and DFE, BER is improved to $< 1\text{e}-5$

ORX Sensitivity

48-Gb/s PAM4 Optical Input



Decoded 6-Gb/s Output



- PAM-4 optical input with 4.8-dB extinction ratio
- Under $1e-12$ BER target, -8.2-dBm sensitivity at 28-Gb/s NRZ is achieved
- Under $2.4e-4$ BER target, -5.1-dBm sensitivity at 48-Gb/s PAM-4 is achieved

Comparison Table

	JSSC'21 [1]	OJCAS'21[2]	JSSC'22 [3]	RFIC'23 [4]	VLSI'24 [5]	This Work
Technology	65nm CMOS	40nm CMOS	28nm CMOS	28nm CMOS	22nm FinFET	28nm CMOS
Data Rate (Gb/s)	16 (Duobinary)	36 (PAM-4)	100 (PAM-4)	42.7 (NRZ)	50 (NRZ)	48 (PAM-4)
PD Capacitance (fF)	180	100	70	N/A	100	60
PD Responsivity (A/W)	0.8	0.8	1	0.8	0.48	0.75
NRZ OMA Sens. at BER 1e-12 (dBm)	-11.6	N/A	-11.1 @56Gb/s	-3.6	-6	-8.2 @28Gb/s
PAM-4 OMA Sens. at BER 2.4e-4 (dBm)	N/A	-4.8*	-8.9	N/A	N/A	-5.1
RX EQ Capabilities	N/A	2-tap DFE	2-tap FFE + 2-tap DFE	CTLE	CTLE + 2-tap FFE	2-tap FFE + 2-tap DFE
Area (mm²)	0.09	0.23	0.45	0.11**	0.32 (TIA + RX)	0.06
Power (mW)	4.0 (TIA)	11.2 (ORX)	128.8 (RX)	117 (TIA) 381 (RX) 145.2** (RX)	15.8 (TIA) 75.9 (ORX)	13.1 (TIA) 61.4 (RX)
Efficiency (pJ/bit)	0.25	0.7	4.0	1.17 3.9	3.4 0.38 1.5	0.27 1.28
FoM (Gbps/mm²/mW)	2570	473	1725	889	622	2589

*Estimated from reported sensitivity curve

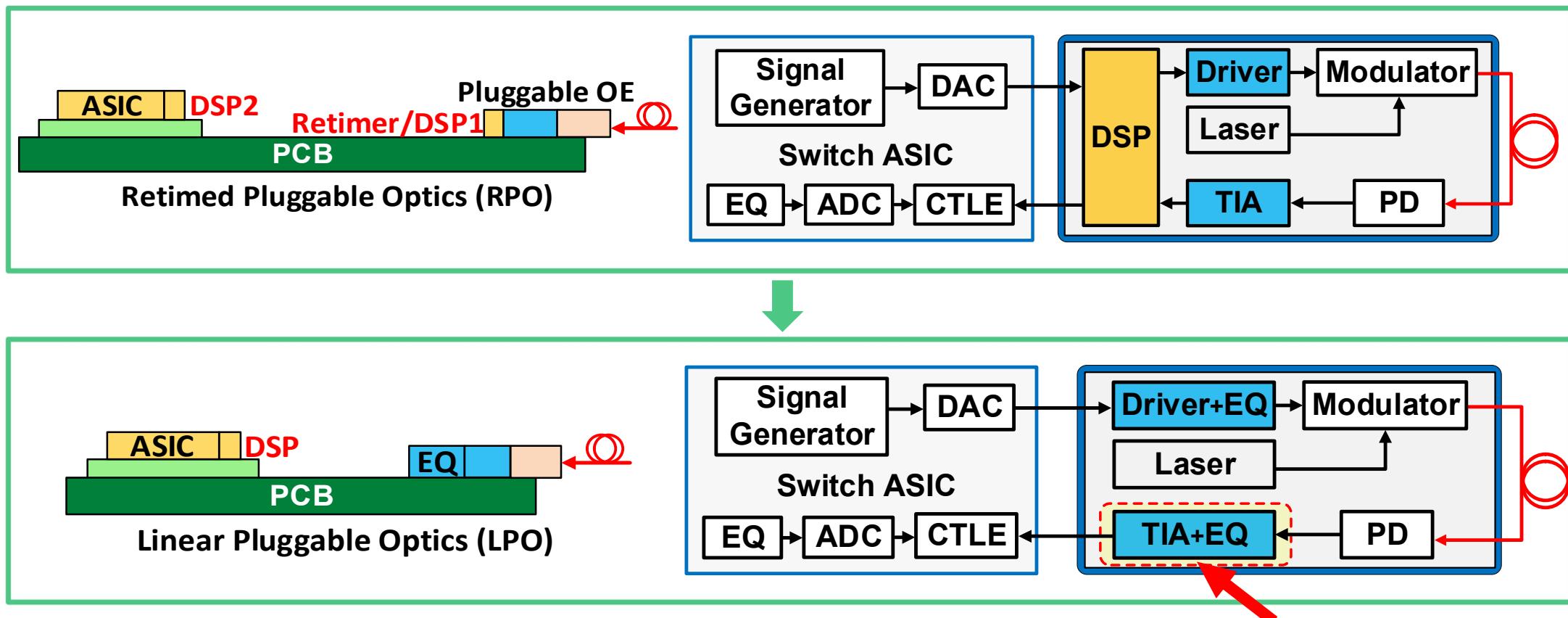
**CDR included

FoM = Data Rate / Area / Input OMA Sensitivity

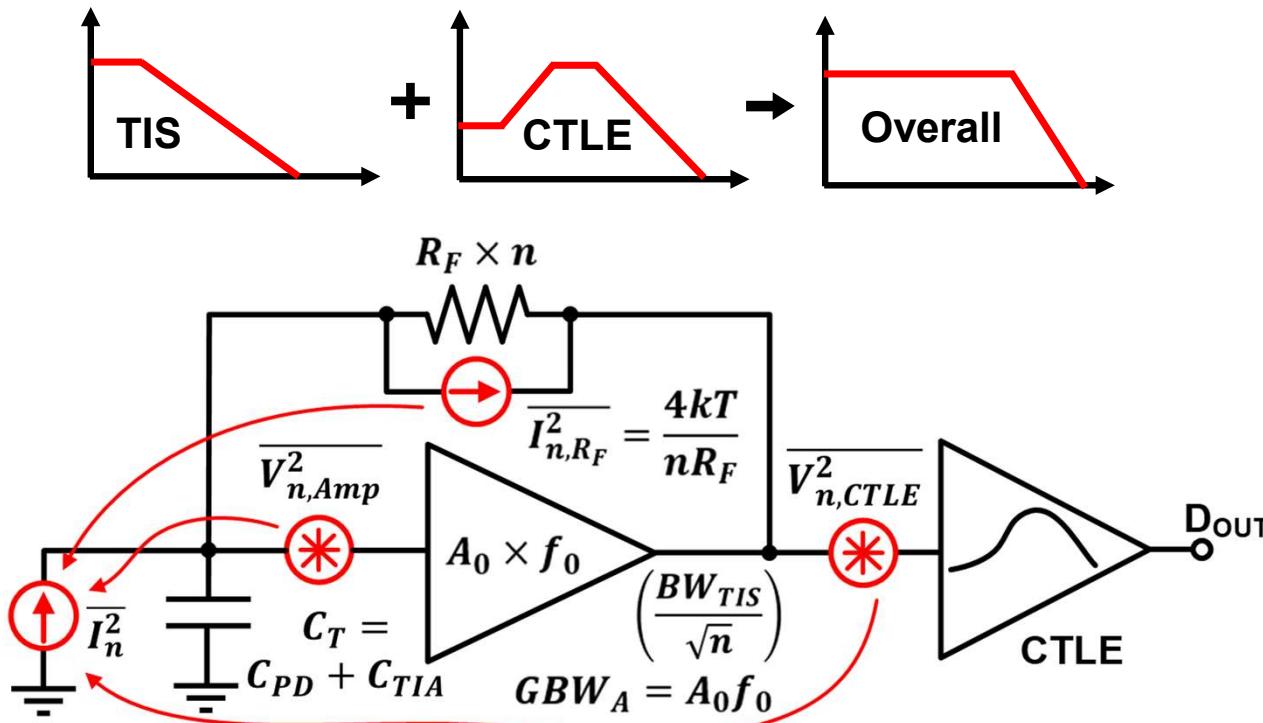
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Motivation



Architectural Consideration

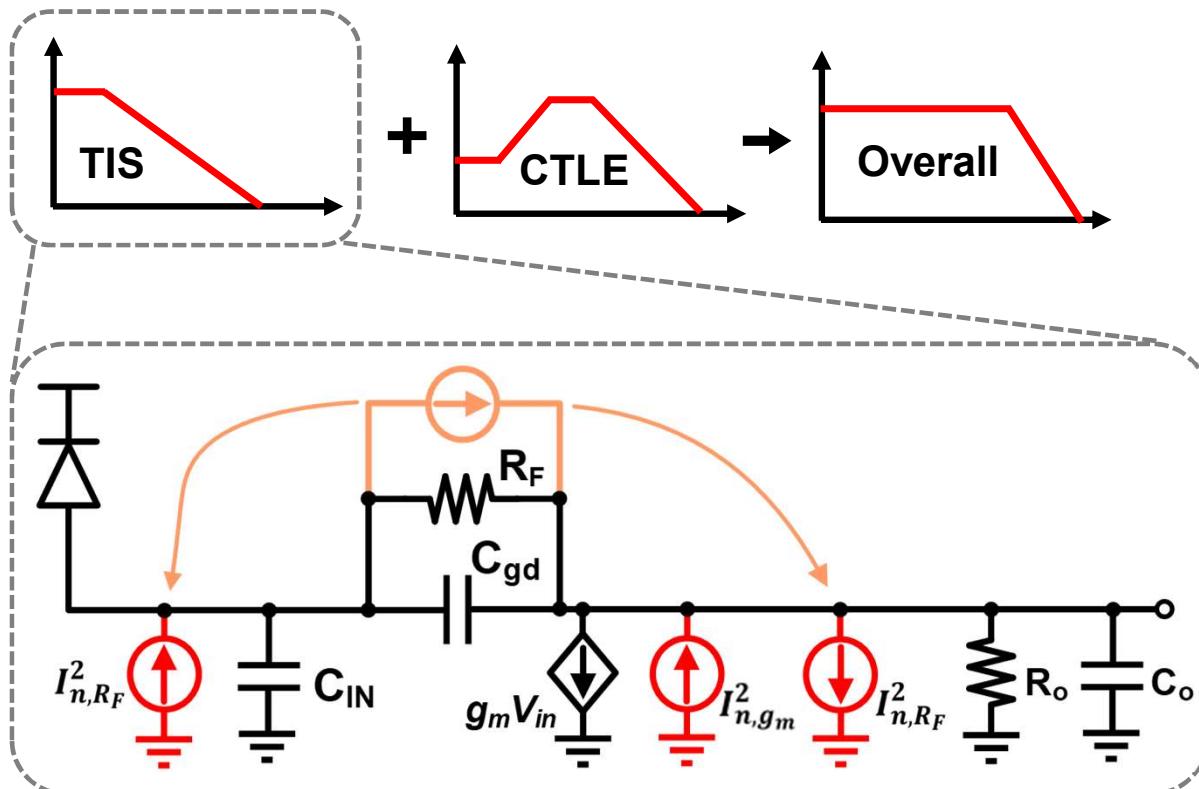


- Low-BW TIS + CTLE is used to break the BW-noise trade-off
- Increasing n reduces white noise terms, while f^2 and f^4 color noise terms remain unchanged
- Large scaling factor n resulting in reduced BW_{TIS} , necessitating higher peaking from CTLE

$$R_F = \frac{(A_0 + 1)\omega_A}{C_T BW_{TIS}^2} \approx \frac{GBW_A}{2\pi C_T BW_{TIS}^2}$$

$$\begin{aligned} i_{n,TIS|CTLE}^2(f) &= \\ &\underbrace{\frac{4kT}{R_F n} + \frac{4kT\gamma}{g_m R_F^2 n^2} + 4kT\gamma \times \frac{(2\pi C_T)^2}{g_m} f^2}_{i_{n,TIS}^2(f)} \\ &+ \underbrace{\frac{4kT\gamma}{g_{m,eq} R_F^2 n^2} + \frac{4kT\gamma}{g_{m,eq} R_F^2} \left(\frac{f}{BW_{TIS}}\right)^4}_{i_{n,CTLE}^2(f)} \end{aligned}$$

Architectural Consideration



- I_{n,R_F}^2 is split at TIS input and output

- TIS transfer function

$$Z_{TIS}(s) = \frac{-R_o(g_m n R_F - 1 - s C_{gd} n R_F)}{1 + g_m n R_F + s K_1 + s^2 K_2}$$

- TIS output impedance

$$Z_o(s) = \frac{R_o[1 + s n R_F (C_{gd} + C_{IN})]}{1 + g_m n R_F + s K_1 + s^2 K_2}$$

$$K_1 = C_{IN}(R_o + n R_F) + C_o R_o + C_{gd} n R_F (1 + g_m R_o)$$

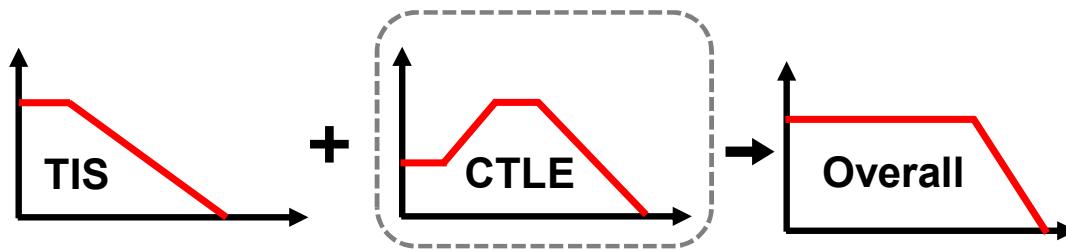
$$K_2 = n R_F R_o (C_{IN} C_o + C_{IN} C_{gd} + C_{gd} C_o)$$

- Noise PSD at TIS output

$$S_{TIS,out}(s) = I_{n,R_F}^2 |Z_{TIS} - Z_o|^2 + I_{n,g_m}^2 |Z_o|^2$$

PSD: power spectral density

Architectural Consideration



- Transfer function of an ideal unity-gain CTLE stage that recovers the full BW

$$H_{CTLE}(s) = \frac{1 + g_m R_F + s K_1 + s^2 K_2}{(1 + g_m R_a) \left(1 + \frac{s}{n Q 2\pi f_{TIS}} + \frac{s^2}{(n 2\pi f_{TIS})^2} \right)}$$

- Zeros of CTLE cancel the poles of TIS

$$Z_{TIS}(s) \times H_{CTLE}(s) = \frac{-R_o(g_m n R_F - 1 - s C_{gd} n R_F)}{(1 + g_m R_a) \left(1 + \frac{s}{n Q 2\pi f_{TIS}} + \frac{s^2}{(n 2\pi f_{TIS})^2} \right)}$$

- Noise PSD at CTLE output

$$S_{CTLE,out}(s) = I_{n,R_F}^2 |(Z_{TIS} - Z_o) \times H_{CTLE}|^2 + I_{n,g_m}^2 |Z_o \times H_{CTLE}|^2$$

- Thermal noise of feedback resistor R_F

$$I_{n,R_F}^2 = 4kT/nR_F$$

- Channel thermal noise

$$I_{n,g_m}^2 = 4kT\gamma g_m$$

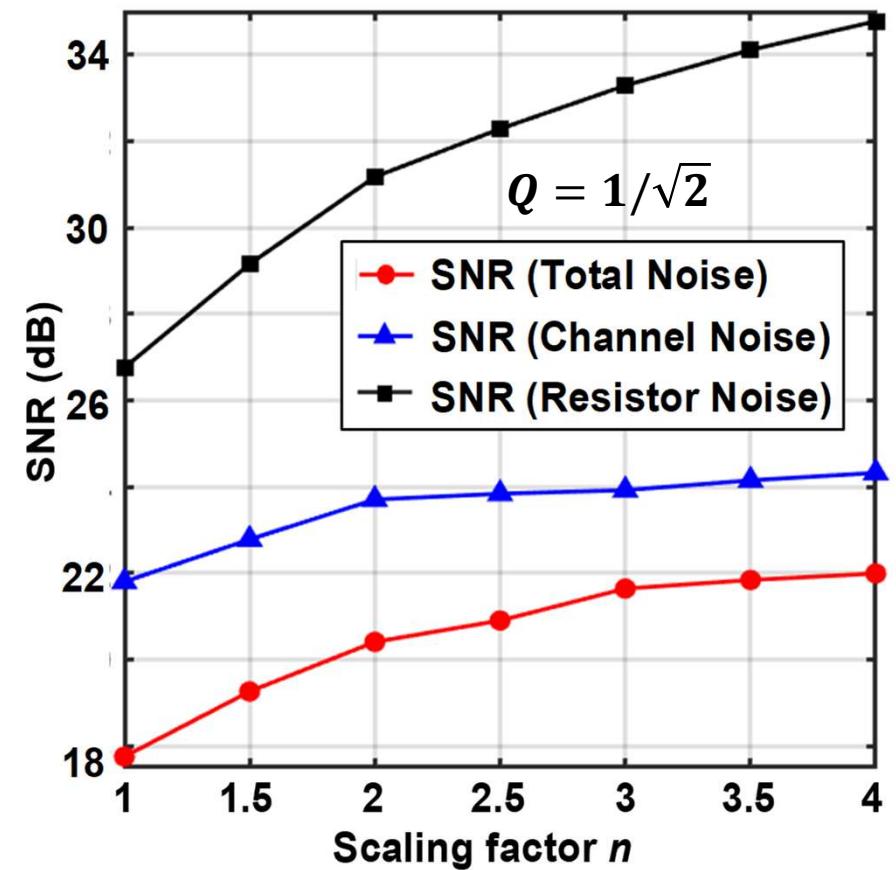
- RMS noise at CTLE output

$$V_{noise,out} = \sqrt{\int_0^\infty S_{CTLE,out}(s) df}$$

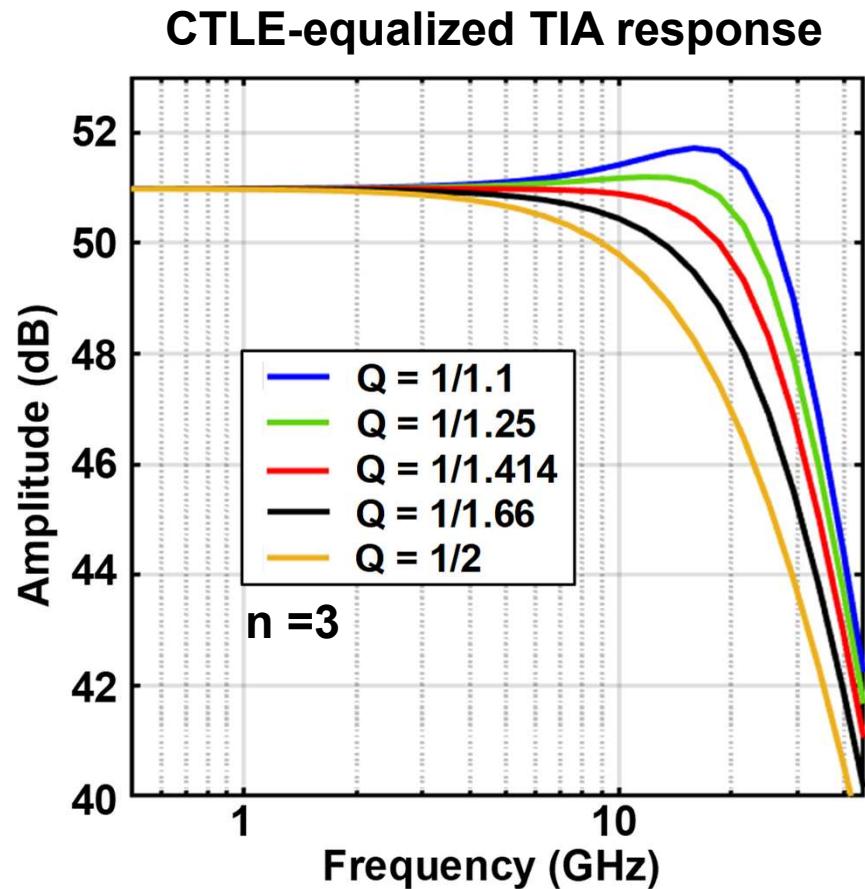
Architectural Consideration

- SNR at CTLE-equalized TIA output
$$SNR = 20 \log_{10} \left(\frac{V_{ISI}}{V_{n,out}} \right)$$
- Worst eye opening V_{ISI} is calculated from the main cursor V_0 and the i_{th} cursors V_i
$$V_{ISI} = |V_0| - 3 \sum_{i \neq 0} |V_i|$$
- SNR improves as n increases
- $n > 3$, color noise component dominated
- White noise is suppressed, while the color noise is not affected

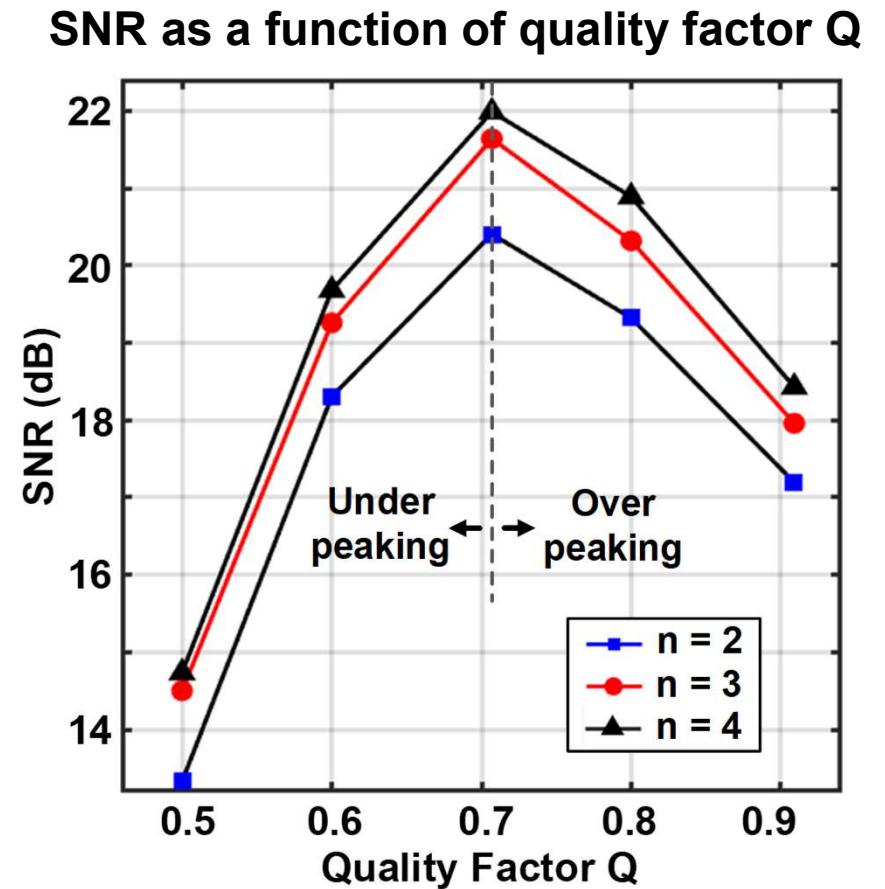
SNR as a function of R_F scaling factor n



Architectural Consideration

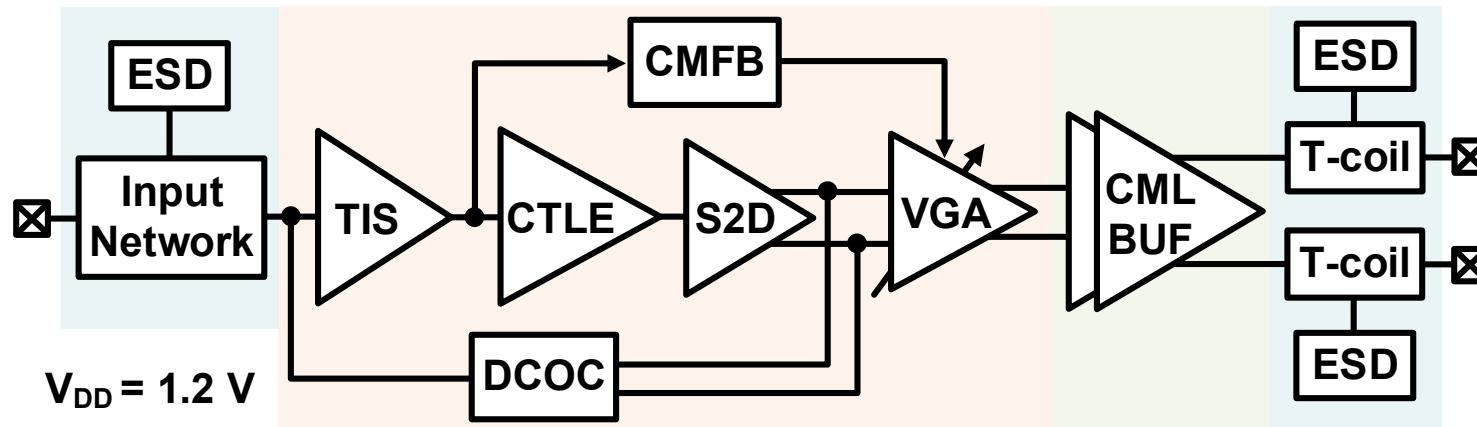


- CTLE over/under-peaking affects TIA noise



- Q variation < 15%, degradation < 2.5 dB

Proposed Architecture



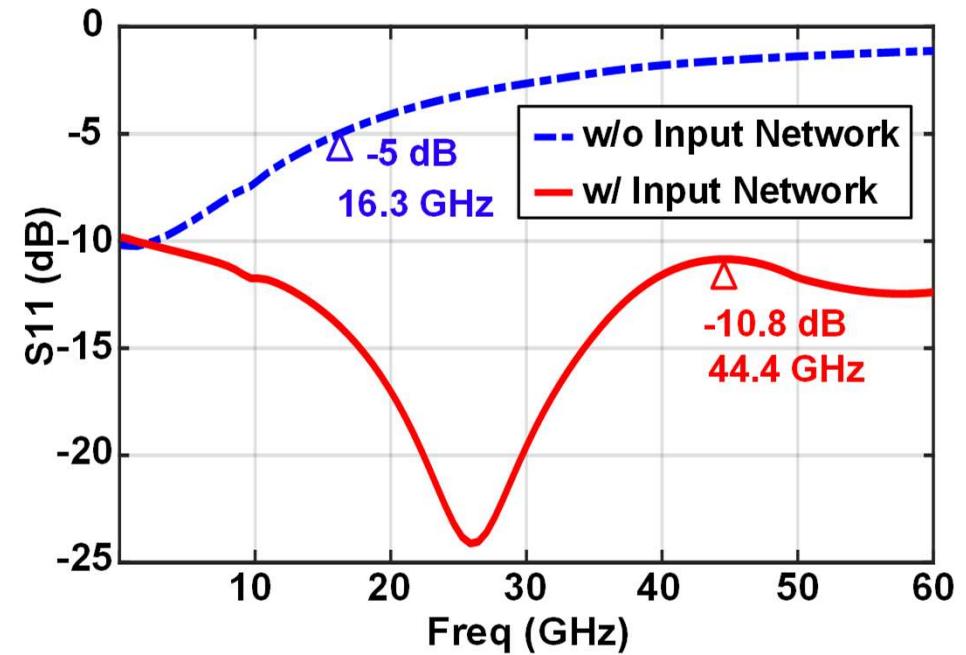
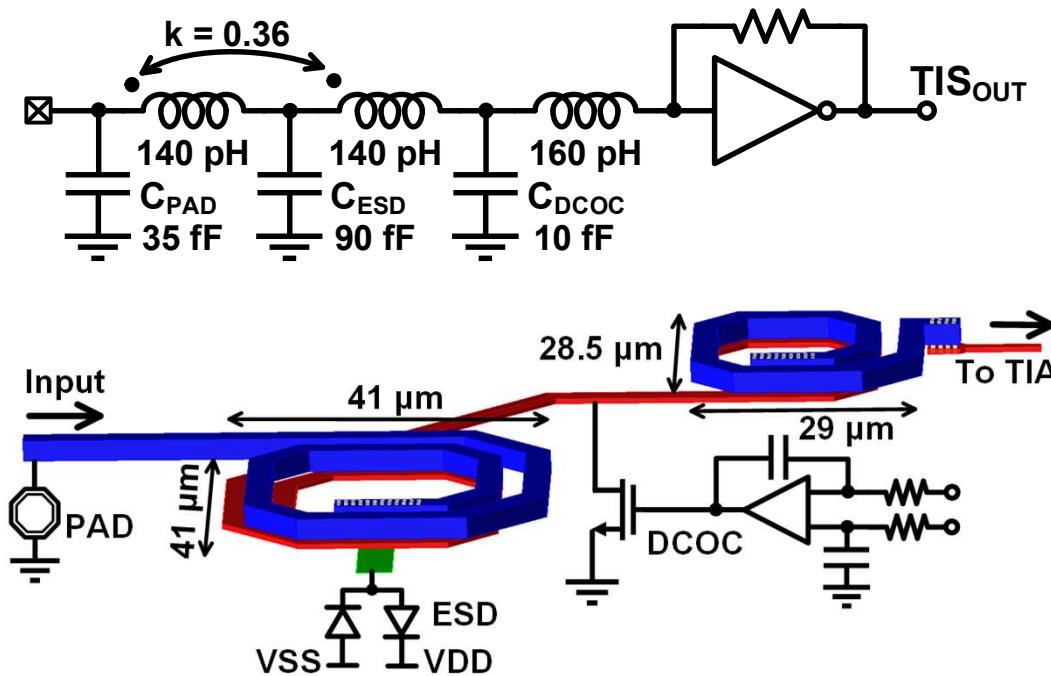
- $n = \sim 3.5$ to obtain a large TIS gain and eliminate the post-amplifier
- Gain and middle/high-frequency peaking of the CTLE are tunable
- S2D conversion is put after the single-ended CTLE instead of the TIS
- T-coils are integrated to optimize return loss and relieve BW degradation from ESD

CMFB: common-mode feedback; S2D: single-to-differential

Outline

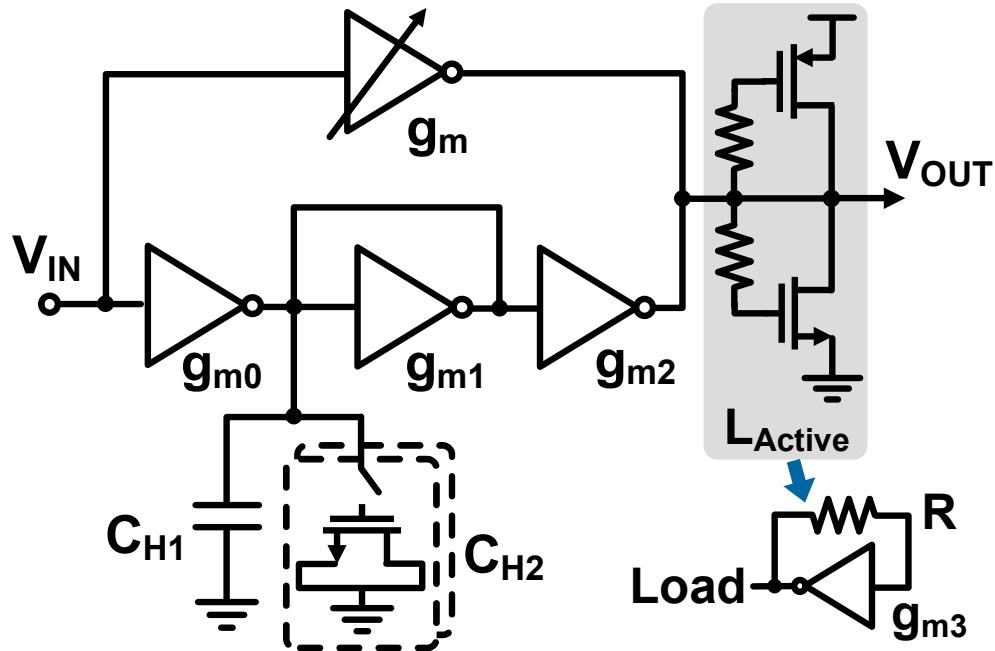
- › Background
- › PAM-4 Optical Receiver Data Path
- › **PAM-4 Optical Receiver Front End**
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TIS with Multi-Peaking Input Network



- Multi-peaking input network to distribute parasitic capacitance
- Multi-layer stacked T-coil and inductor are custom designed
- Good broadband impedance matching under heavy capacitive loading achieved

Single-Ended Inverter-Based CTLE



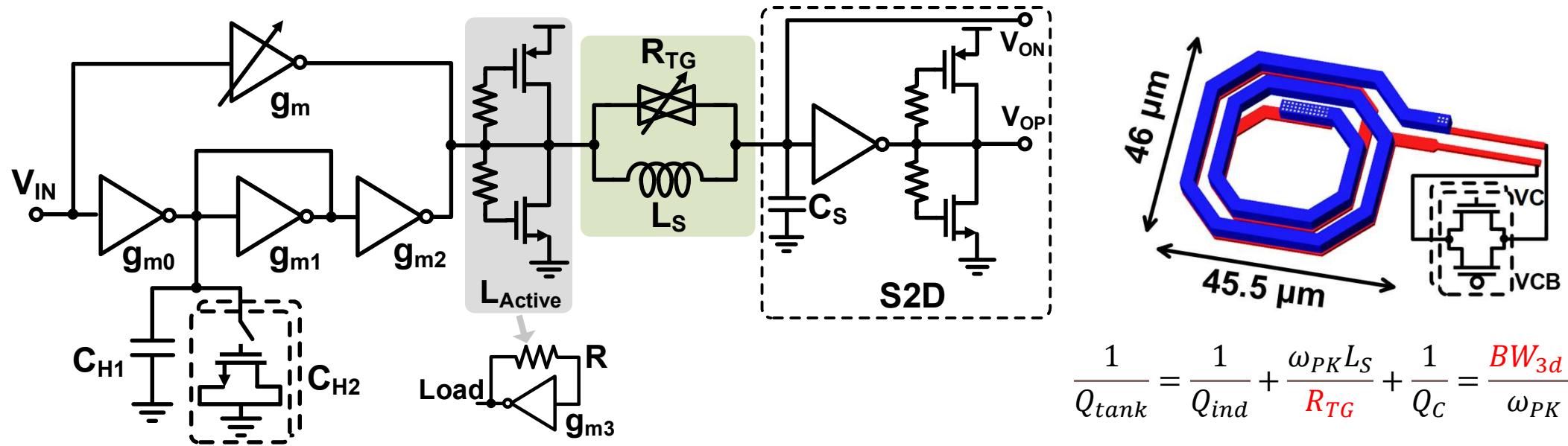
- Gm-C filter create one pole at $g_{m1}/(C_{H1} + C_{H2})$

- CTLE response

$$\begin{aligned}
 H(s) &= [H_M(s) - H_L(s)] \cdot L_{Active} \\
 &= \left[g_m - \frac{g_{m0}g_{m2}}{g_{m1}} \cdot \frac{1}{1 + s(C_{H1} + C_{H2})/g_{m1}} \right] \cdot \frac{sRC_{gs}}{2g_{m3}}
 \end{aligned}$$

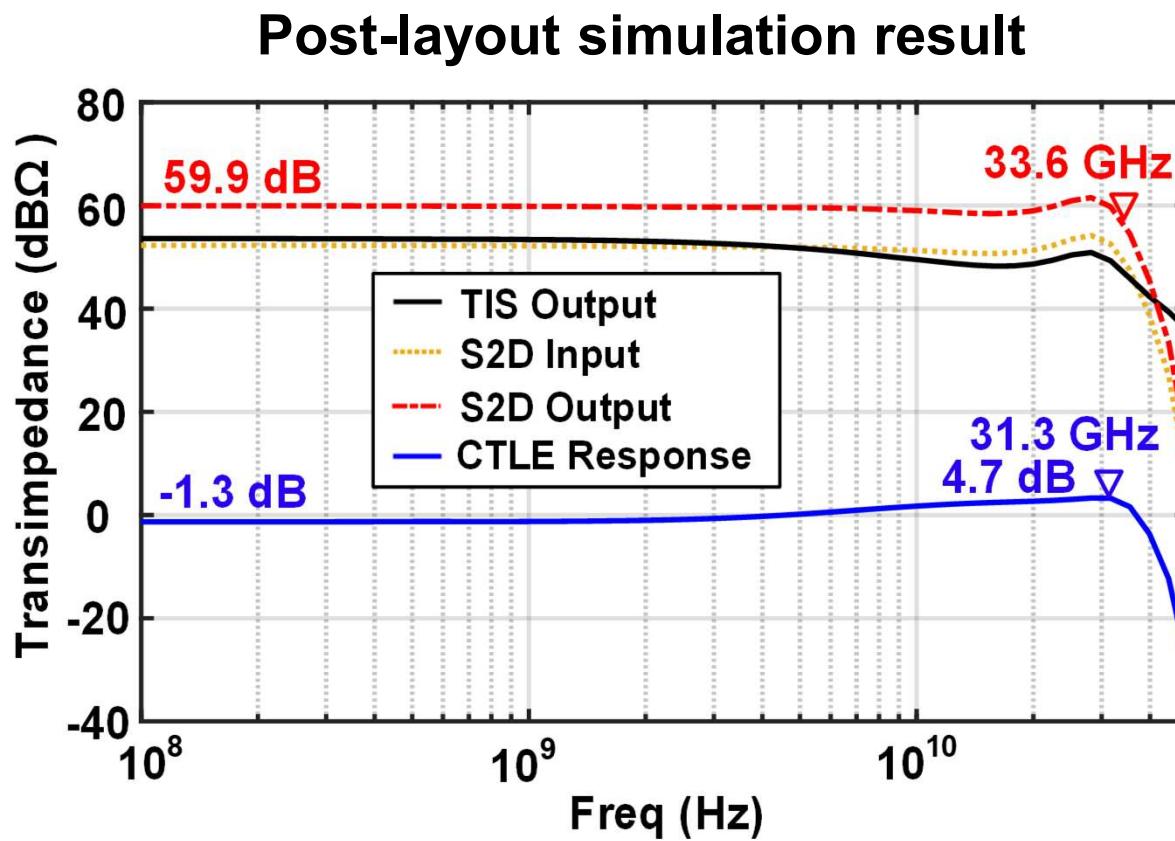
- High f_T of PMOS in deep sub-micron CMOS technologies
- CTLE engages two parallel paths: main and low-pass paths
- Peaking is created by subtracting the low-pass path from the main path
- 3-bit dc gain control and 2-bit middle-frequency (MF) tuning implemented

CTLE with Q-Shaping Inductor



- Accommodate BW variation of TIA caused by bond wires and input capacitance
- Tunable Q: programmable transmission gate R_{TG} in parallel with a 670-pH inductor L_s
- S2D circuit is implemented by a unity gain buffer with active inductor load

Simulated Frequency Response



At TIS output:

- 53.6 $\text{dB}\Omega$ with $\text{BW}_{3\text{dB}}$ of 7.1-GHz
- $\text{BW}_{6\text{dB}}$ of 15.1 GHz, 23.8 GHz and 33.7 GHz

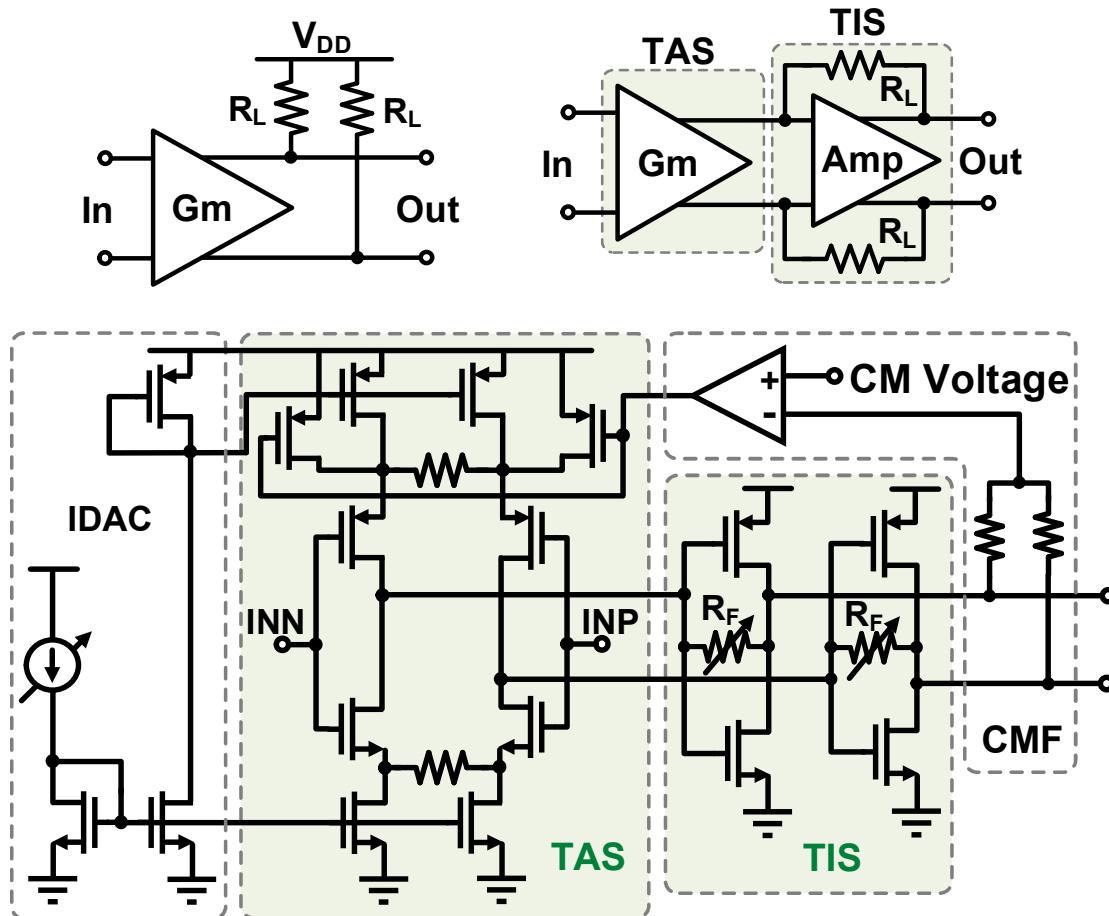
CTLE response:

- 6-dB peaking at 31.3 GHz

At S2D output:

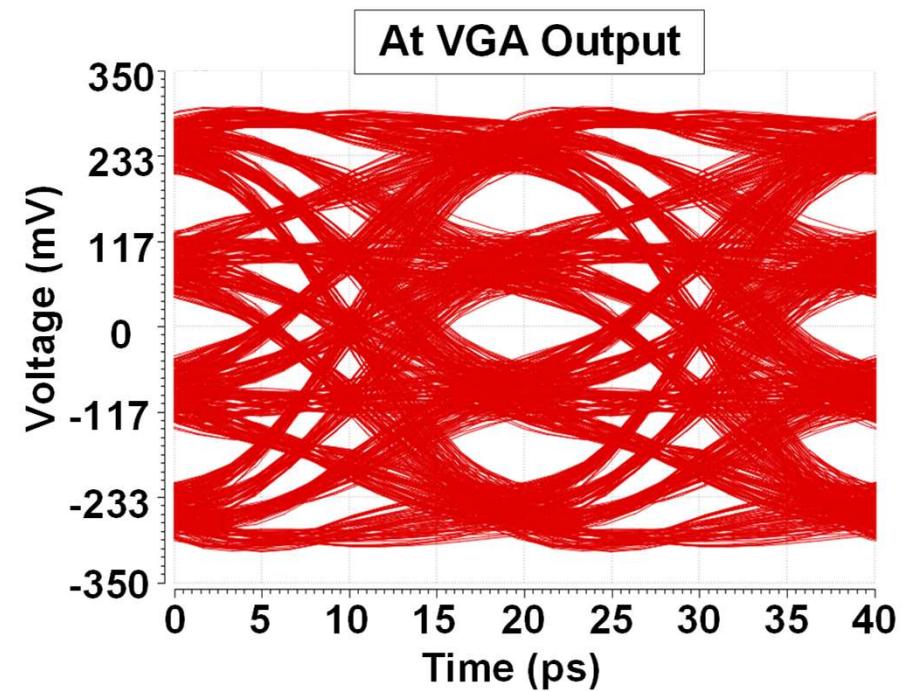
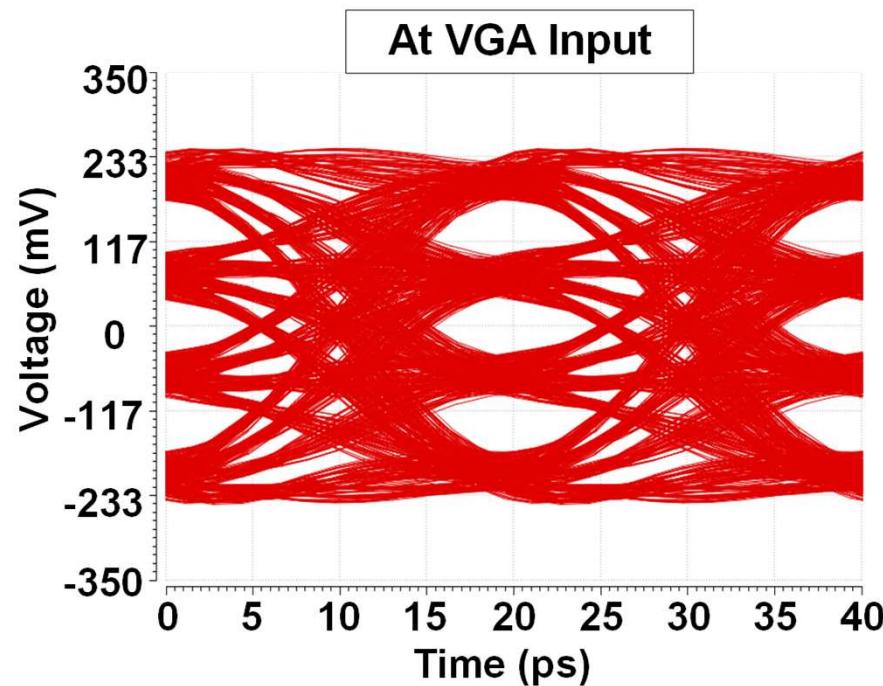
- 59.9 $\text{dB}\Omega$ with $\text{BW}_{3\text{dB}}$ of 33.6 GHz

VGA Design



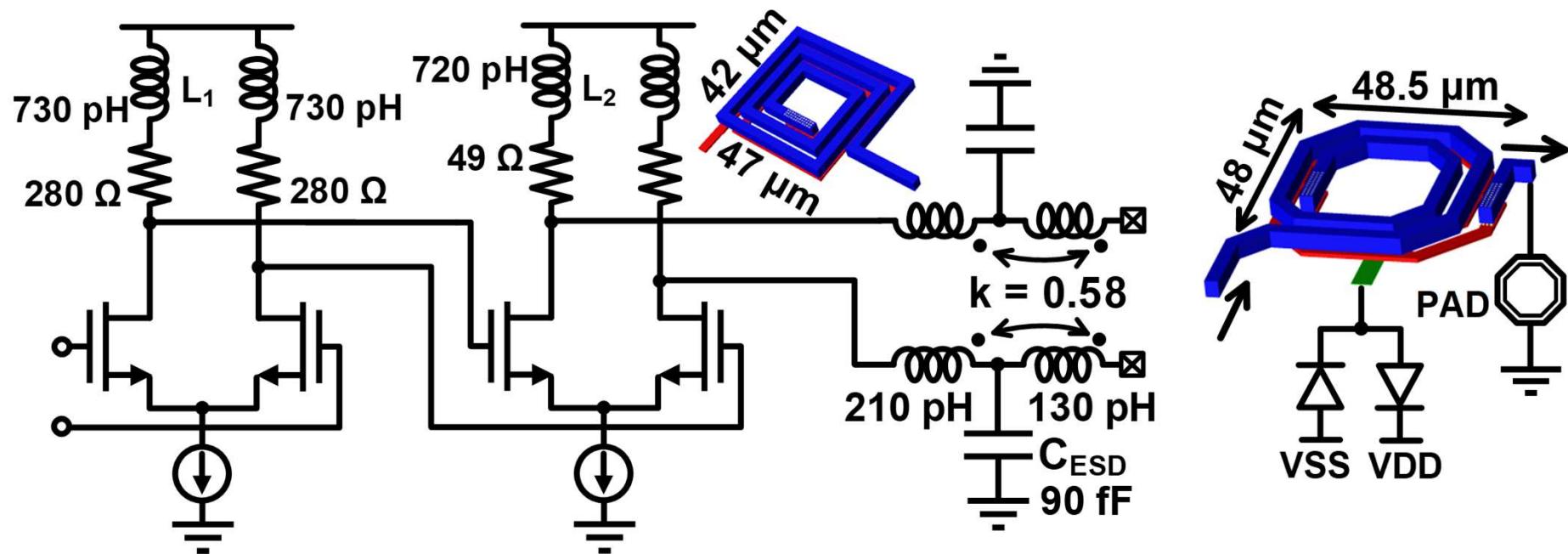
- NMOS- or PMOS-only input pairs exhibit compromised linearity
- CMOS input pairs of both TAS and TIS improve linearity
- Combine the tunability of both G_m and R_F 3-bit G_m control and 2-bit R_F control
- Tail current sources to improve immunity to supply variations and CM rejection
- Source degeneration resistor to further enhance linearity
- Gain: -2.4 dB to 7.3 dB

Simulated Eye Diagrams



- TIA input amplitude of $600 \mu\text{A}_{\text{pp}}$
- Simulated 100-Gb/s PAM-4 eye diagrams at VGA input and output
- VGA output: ratio level mismatch (RLM) > 96%

Output BUF Design

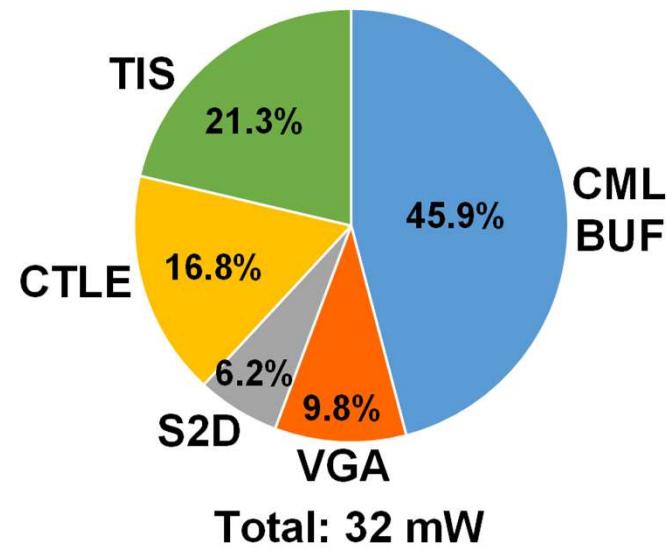
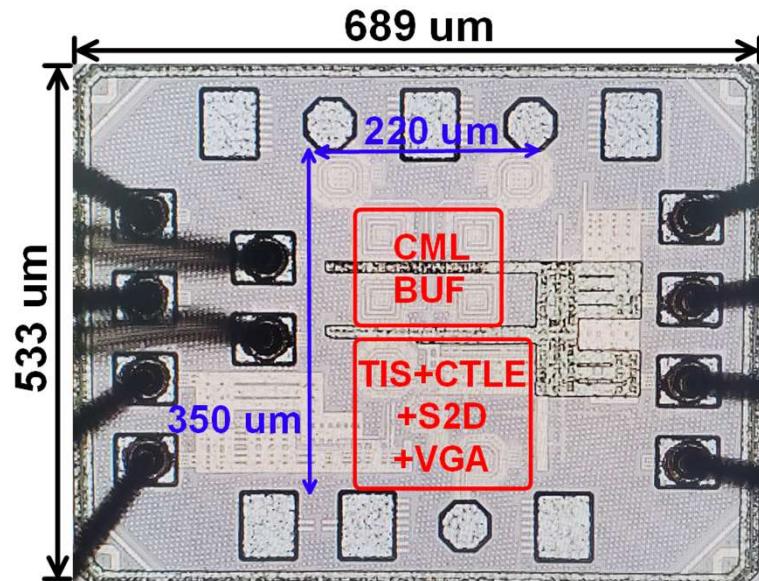


- Two cascaded differential pairs with shunt-inductive peaking to drive 50- Ω off-chip load
- Multi-layer stacked T-coils to accommodate ESD capacitance
- Buffer with T-coil and ESD diodes provides 0-dB gain with 42-GHz BW

Outline

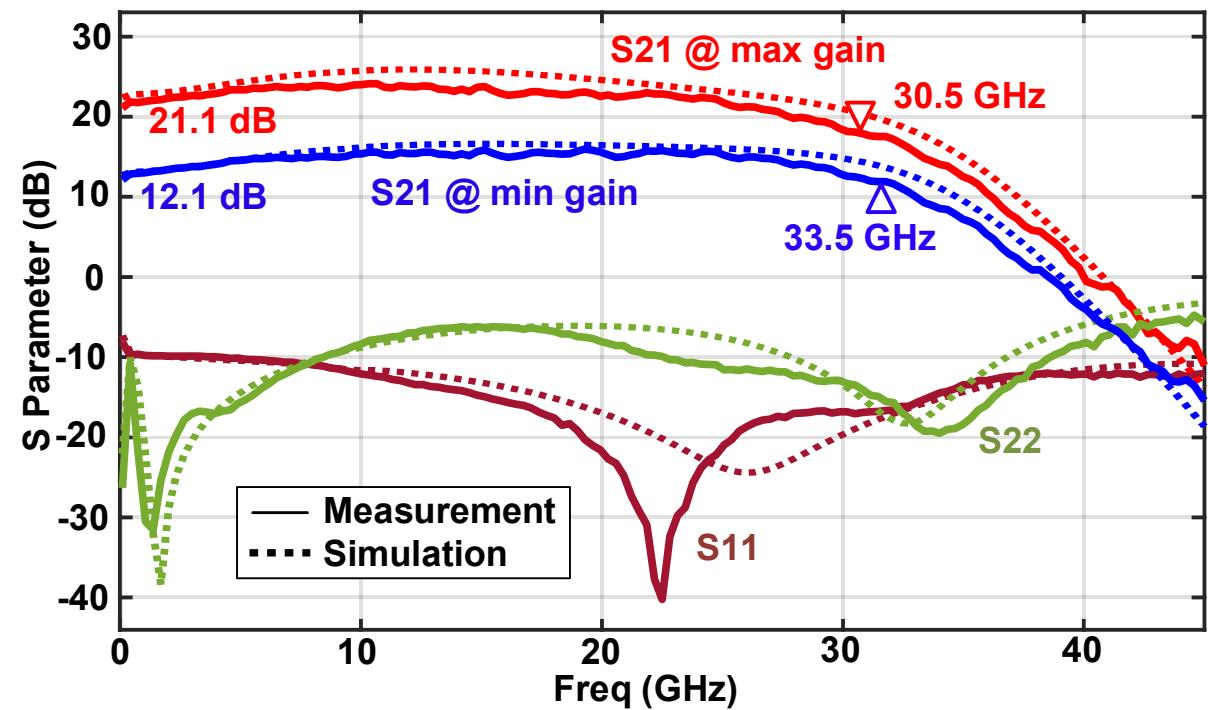
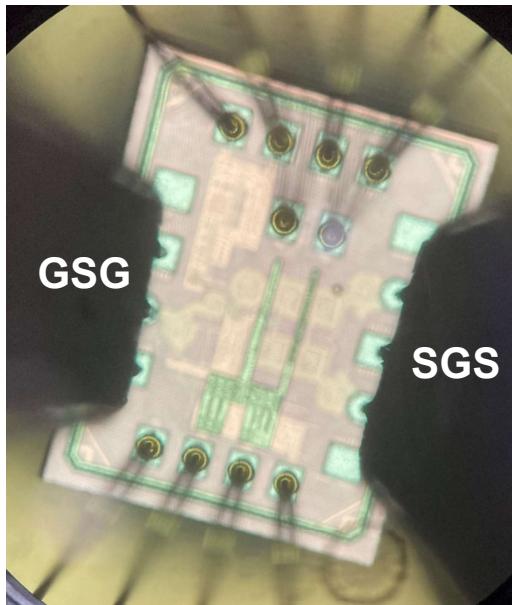
- › Background
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Die Photo and Power Breakdown



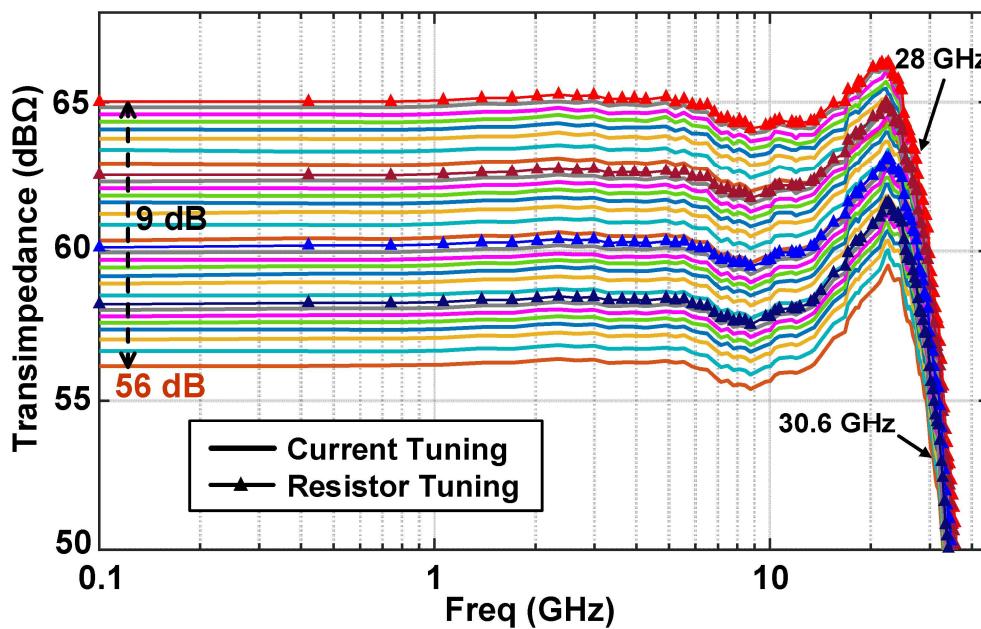
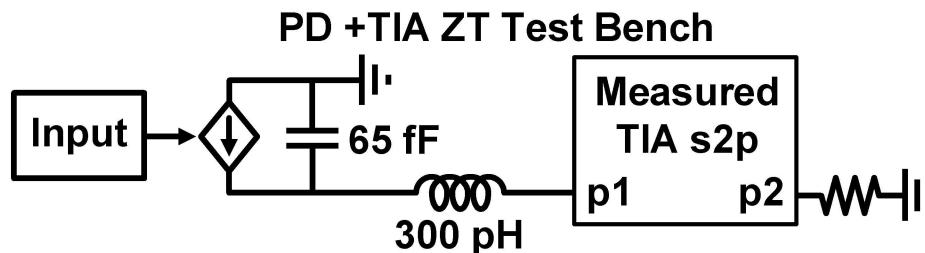
- Fabricated in a 28-nm bulk CMOS technology
- $0.69 \times 0.53 \text{ mm}^2$ area defined by the pad frame
- 32 mW power consumption including output buffer from a 1.2-V supply

Small Signal Measurement: S-Parameter

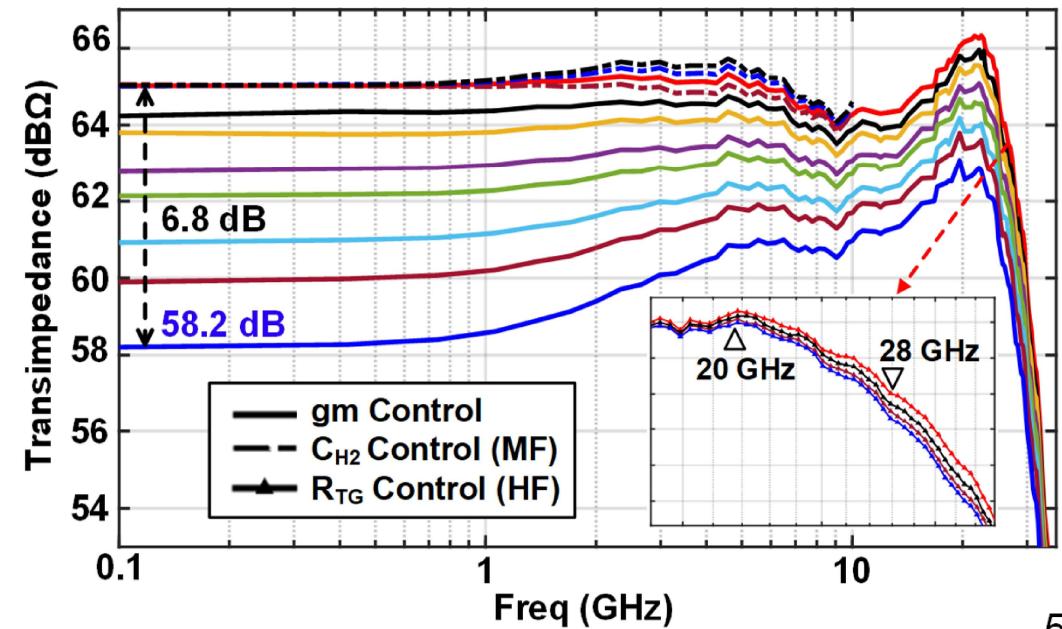


- Four-port S-parameter measurement up to 50 GHz
- S21: maximum gain of 21.1 dB with a BW of 30.5 GHz
- S11 and S22 lower than -6 dB up to 40 GHz

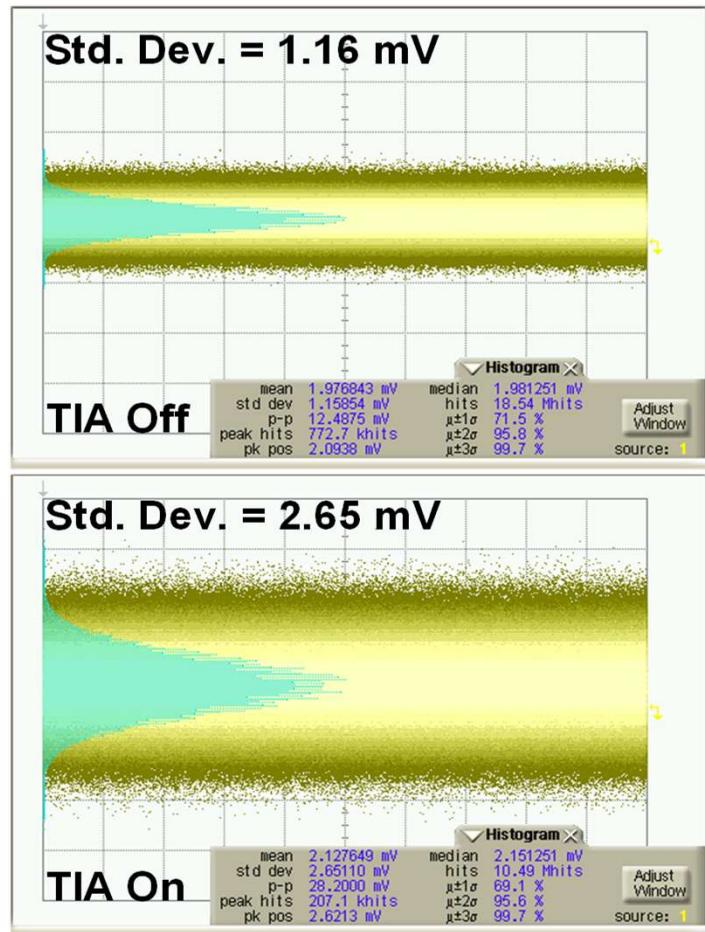
Small Signal Measurement: Transimpedance



- ZT: max. gain of 65 $\text{dB}\Omega$ with a 28 GHz BW
- 9-dB gain control range with an average step of 0.3 dB, overall BW variation < 3 GHz
- CTLE: dc gain control range of 6.8 dB



Noise Measurement



Single-ended output noise distribution

- 80-GHz sampling oscilloscope
- Noise from oscilloscope de-embedded

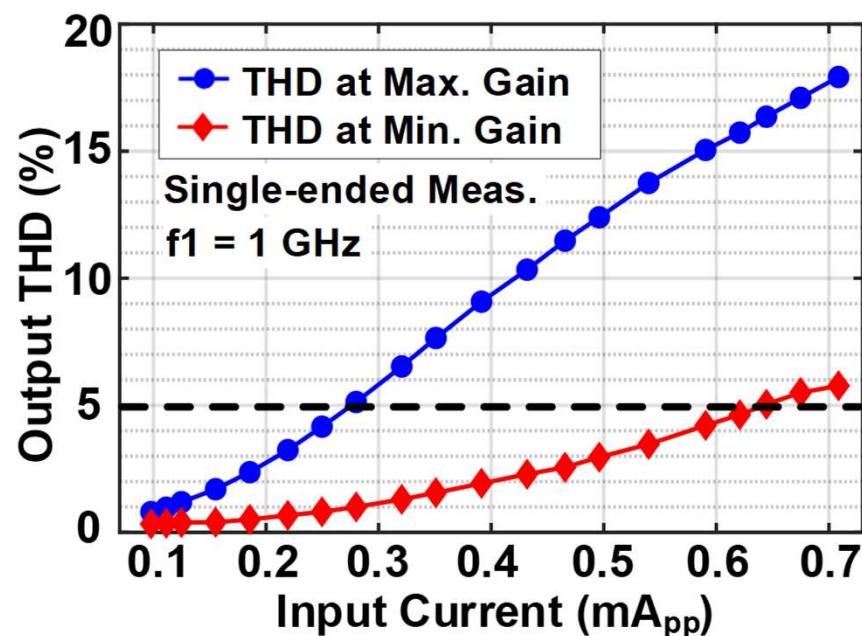
Input-referred current noise

$$i_{n,in}(rms) = \frac{2 \times \sqrt{(2.65mV)^2 - (1.16mV)^2}}{10^{\frac{(65)}{20}}} = 2.68 \mu A_{rms}$$

Average input-referred current noise density

$$2.68 \mu A_{rms} / \sqrt{28 \text{ GHz}} = 16 pA / \sqrt{\text{Hz}}$$

THD Measurement



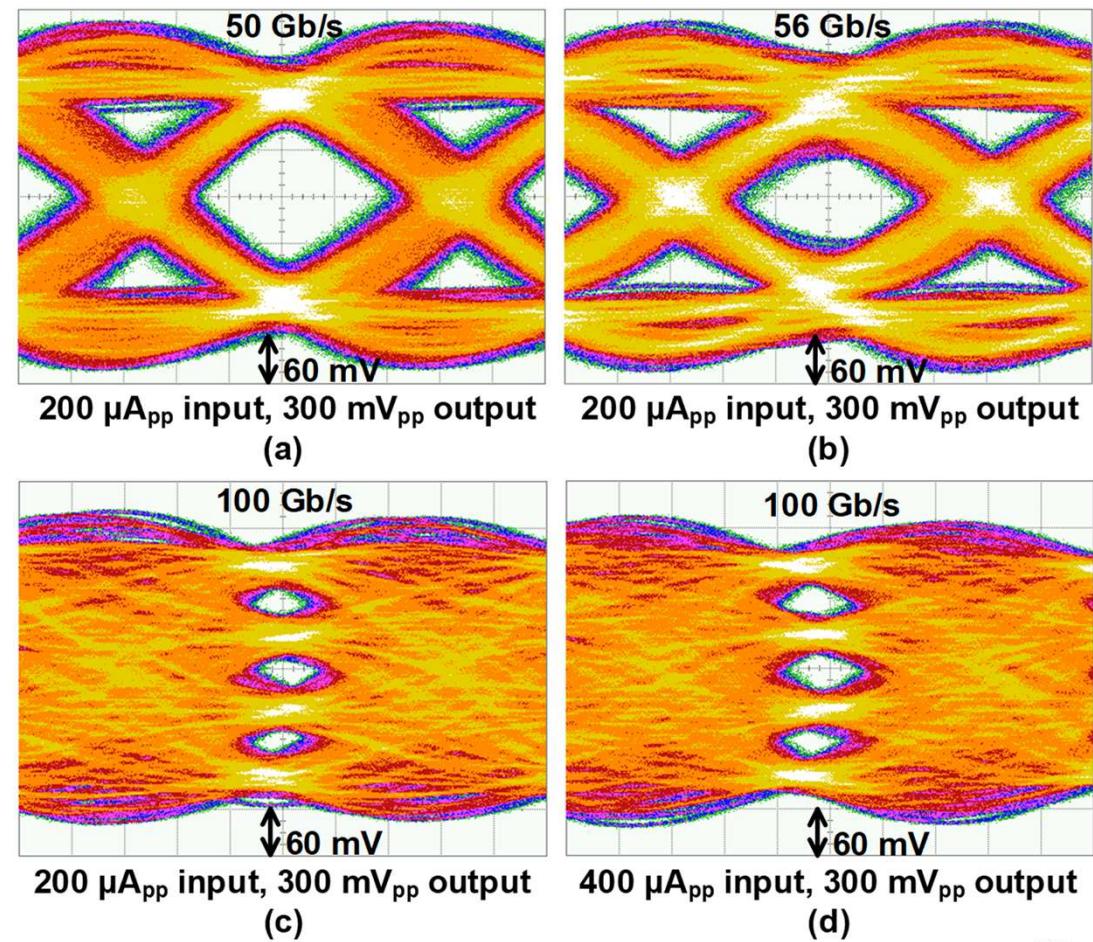
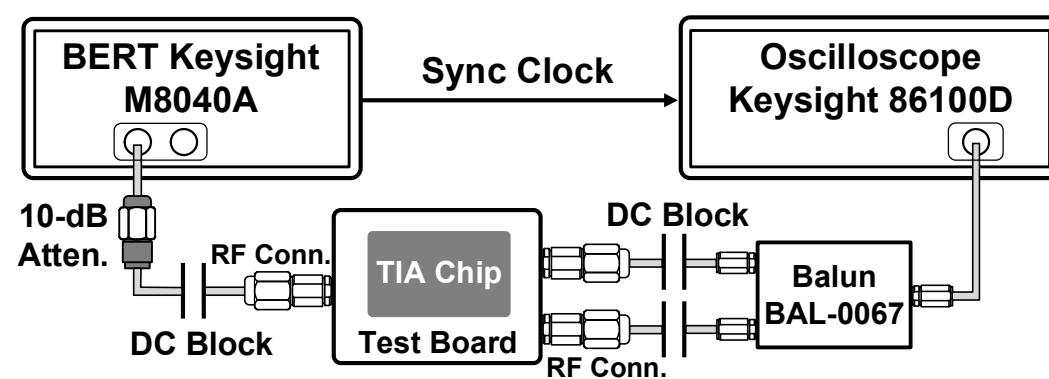
Single-ended total harmonic distortion (THD)

- 67-GHz spectrum analyzer
- 1-GHz fundamental frequency
- 10 harmonics counted

Within a THD of 5%

- At max. gain: $280 \mu\text{A}_{\text{pp}}$ input, $\sim 500 \text{ mV}_{\text{pp}}$ output
- At min. gain: $640 \mu\text{A}_{\text{pp}}$ input, $\sim 400 \text{ mV}_{\text{pp}}$ output

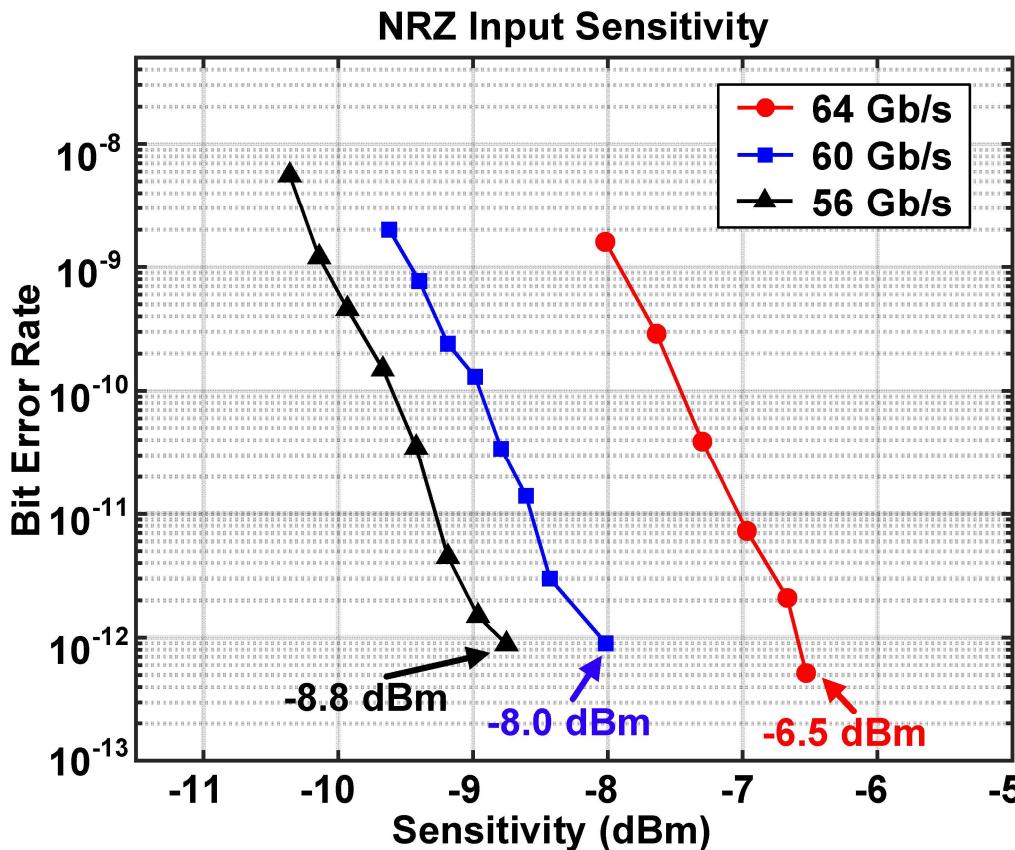
Time Domain Measurement



Time domain measurement setup

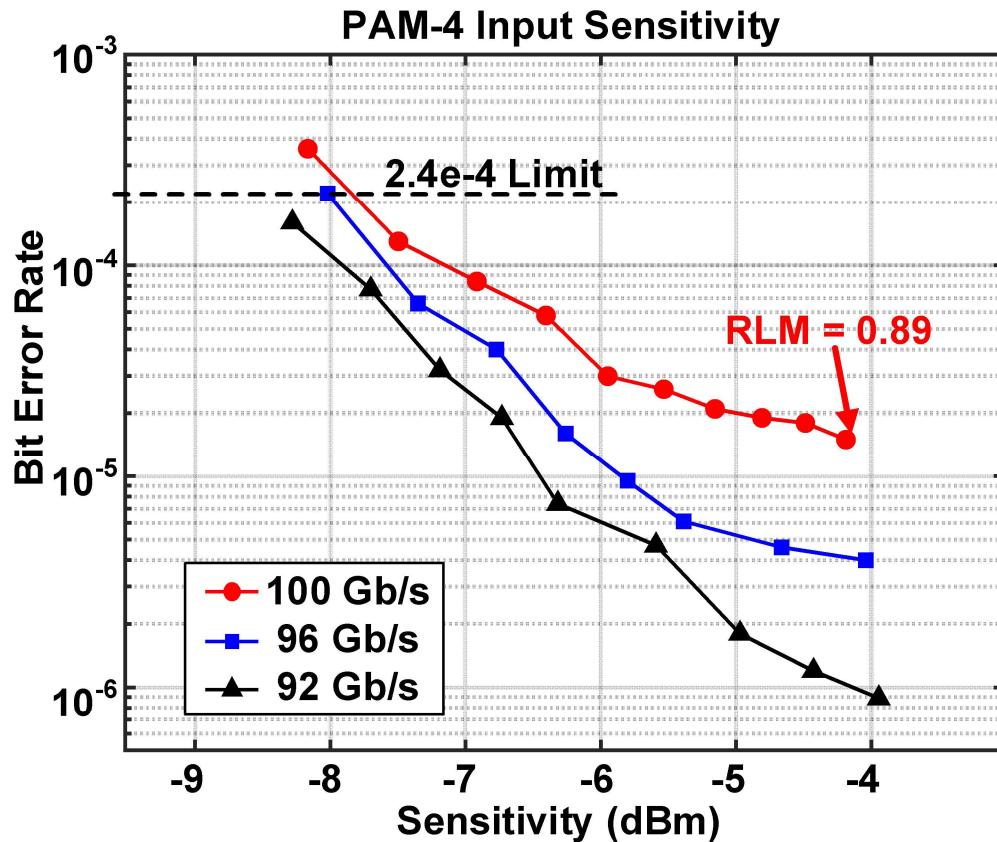
- 64-Gbaud bit error rate tester (BERT)
- 10-dB attenuator at data input
- TIA differential output combined by a balun
- More than 10k UI of PRBS-9 pattern

BER Measurement: NRZ



- BER at different amplitudes of electrical input signals is measured
 - Assume a PD responsivity of 0.75 A/W
 - Estimated BER versus input OMA sensitivity
- Under $1e-12$ BER
 - -6.5-dBm sensitivity at 64 Gb/s
 - -8.8-dBm sensitivity at 56 Gb/s

BER Measurement: PAM-4



- BER at different amplitudes of electrical input signals is measured
 - Assume a PD responsivity of 0.75 A/W
 - Estimated BER versus input OMA sensitivity
- Under 2.4e-4 pre-FEC limit
 - -7.8-dBm sensitivity at 100 Gb/s
 - With -4-dBm input at 100 Gb/s, 1.5e-5 BER achieved with a RLM of 0.89

Comparison Table

Reference	ESSCIRC'18 [6]	JSSC'22 [7]	JSSC'22 [3]	JSSC'23 [8]	VLSI'23 [9]	SSCL'23 [10]	SSCL'24 [11]	This Work
Technology	28nm CMOS	22nm FinFET	28nm CMOS	16nm FinFET	12nm FinFET	22nm FD-SOI	28nm CMOS	28nm CMOS
Data Rate (Gb/s)	112*	128*	100	112	90	106.25	85*	100*
Gain (dBΩ)	65	59.3	68.6	63	65	74	65	65
BW (GHz)	60	45.5	20.8	32	25	28	24	28
THD@ Input Current, Output Amplitude)	<5%@ 1mA _{pp} , N/A	<5%@ 330μA _{pp} , 304mV _{pp}	NA	<8%@ 670μA _{pp} , 336mV _{pp}	<9%@ 600μA _{pp} , N/A	<4%@2.46 mA _{pp} , 550mV _{pp}	<1.77%@ 330μA _{pp} , 660mV _{pp}	<5%@ 640μA _{pp} , 400mV _{pp}
Noise (pA/√Hz)	19.3	12.6	17	16.9	13.4	11	10.4	16
Input/Output ESD	No	No	No	Yes (80f)	Yes	Yes	No	Yes (90f)
Power (mW)	107	11.2	117	77	29.2	155	56	32
Efficiency (pJ/bit)	0.96	0.09	1.17	0.69	0.32	1.46	0.66	0.32
FoM**	997	3748	478	739	1522	905	762	1556

*Electrical Measurement

$$**\text{FoM} = \frac{\text{Gain}(\Omega) \times \text{BW}_{3dB}(\text{GHz})}{P_{dc}(\text{mW})}$$

Outline

- › **Background**
- › **PAM-4 Optical Receiver Data Path**
- › **PAM-4 Optical Receiver Front End**
- › **Conclusion**

Conclusion

■ PAM-4 ORX Data Path

- A 48-Gb/s PAM-4 ORX is proposed with a linear TIA and a PAM-4 sampler integrated
- The TIA avoids CTLE and passive inductors, and the sampler incorporates a 2-tap FFE and a 2-tap DFE to mitigate ISI from TIA
- Under 2.4e-4 BER, -5.1-dBm sensitivity is achieved with 1.28-pJ/bit (0.27-pJ/bit for TIA alone) efficiency

■ PAM-4 ORX Front End

- A 100-Gb/s PAM-4 linear TIA is proposed with high inductance density
- A single-ended inverter-based CTLE is implemented, and a current reuse VGA based on a TAS-TIS topology provides a large gain-BW product and high linearity
- 28-GHz BW with a 65-dBΩ gain is achieved, consuming only 32 mW

Publication

- [1] **Chongyun Zhang**, Fuzhan Chen, Li Wang, Lin Wang, and C. Patrick Yue, "Recent advances of high-speed short-reach optical interconnects for data centers," *IEEE Open J. Solid-State Circuits Soc.*, vol. 5, pp. 86-100, 2025.
- [2] **Chongyun Zhang**, Li Wang, Zilu Liu, Fuzhan Chen, Quan Pan, Xianbo Li, and C. Patrick Yue, "A 48-Gb/s half-rate PAM4 optical receiver with 0.27-pJ/bit TIA efficiency, 1.28-pJ/bit RX efficiency, and 0.06-mm² area in 28-nm CMOS," in *Proc. IEEE Symp. VLSI Technol. Circuits (VLSI Technol. Circuits)*, Jun. 2024, pp. 1–2.
- [3] **Chongyun Zhang**, Fuzhan Chen, and C. P. Yue, "A 56-Gb/s PAM-4 transmitter using silicon photonic microring modulator in 40nm CMOS," in *Proc. IEEE Int. Midwest Symp. Circuits Syst. (MWSCAS)*, Aug. 2022, pp. 1-4.
- [4] **Chongyun Zhang**, Xinyi Liu, and C. Patrick Yue, "A compact VCSEL model for high-speed optical interconnect design," in *Proc. Laser Congr. (ASSLLAC)*, Jan. 2021, JTU1A.30.
- [5] Abdekhoda Johar, **Chongyun Zhang**, Li Wang, Reza Sarvari, Reza Navid, and C. Patrick Yue, "A 56-Gb/s PAM-4 injection-locked CDR," in *Proc. IEEE Eur. Solid State Circuits Conf. (ESSC/RC)*, Sep. 2025, accepted.
- [4] Fuzhan Chen, **Chongyun Zhang**, Li Wang, Quan Pan, and C. Patrick Yue, "A 56-Gb/s PAM-4 VCSEL transmitter with piecewise compensation scheme in 40-nm CMOS," *IEEE J. Solid-State Circuits*, early access.
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- [7] **Chongyun Zhang**, Li Wang, Fuzhan Chen, Quan Pan, Xianbo Li, and C. Patrick Yue, "A 48-Gb/s inductorless PAM4 optical receiver with 1.28-pJ/bit efficiency in 28-nm CMOS," *IEEE J. Solid-State Circuits*, major revision.

Acknowledgement

- Supervisor: Prof. C. Patrick Yue

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- All Optical Wireless Lab Members

- Dr. Li Wang
 - Dr. Fuzhan Chen

Reference

- [1] M. G. Ahmed, D. Kim, R. K. Nandwana, A. Elkholly, K. R. Lakshmikumar and P. K. Hanumolu, "A 16-Gb/s -11.6-dBm OMA sensitivity 0.7-pJ/bit optical receiver in 65-nm CMOS enabled by duobinary sampling," *IEEE J. Solid-State Circuits*, vol. 56, no. 9, pp. 2795–2803, Sep. 2021.
- [2] W. Ho, Y. Hsieh, B. Murmann and W. Chen, "A 32 Gb/s PAM-4 optical transceiver with active back termination in 40 nm CMOS technology," *IEEE Open J. Circuits Syst.*, vol. 2, pp. 56–64, 2021.
- [3] H. Li, C. Hsu, J. Sharma, J. Jaussi and G. Balamurugan, "A 100-Gb/s PAM-4 optical receiver with 2-tap FFE and 2-tap direct-feedback DFE in 28-nm CMOS," *IEEE J. Solid-State Circuits*, vol. 57, no. 1, pp. 44–53, Jan. 2022.
- [4] H. Kang, I. Kim, R. Liu, et al., "A 42.7Gb/s Optical Receiver with Digital CDR in 28nm CMOS," in *Proc. IEEE Radio Freq. Integr. Circuits Symp. (RFIC)*, Jun. 2023, pp. 9–12.
- [5] S. Krishnamurthy et al., "A 4×50Gb/s NRZ 1.5pJ/b co-packaged and fiber-terminated 4-channel optical RX," in *Proc. IEEE Symp. VLSI Technol. Circuits (VLSI Technol. Circuits)*, Jun. 2024, pp. 1-2.
- [6] H. Li, G. Balamurugan, J. Jaussi and B. Casper, "A 112 Gb/s PAM4 linear TIA with 0.96 pJ/bit energy efficiency in 28 nm CMOS," in *Proc. IEEE Eur. Solid-State Circuits Conf. (ESSCIRC)*, Sep. 2018, pp. 238–241.

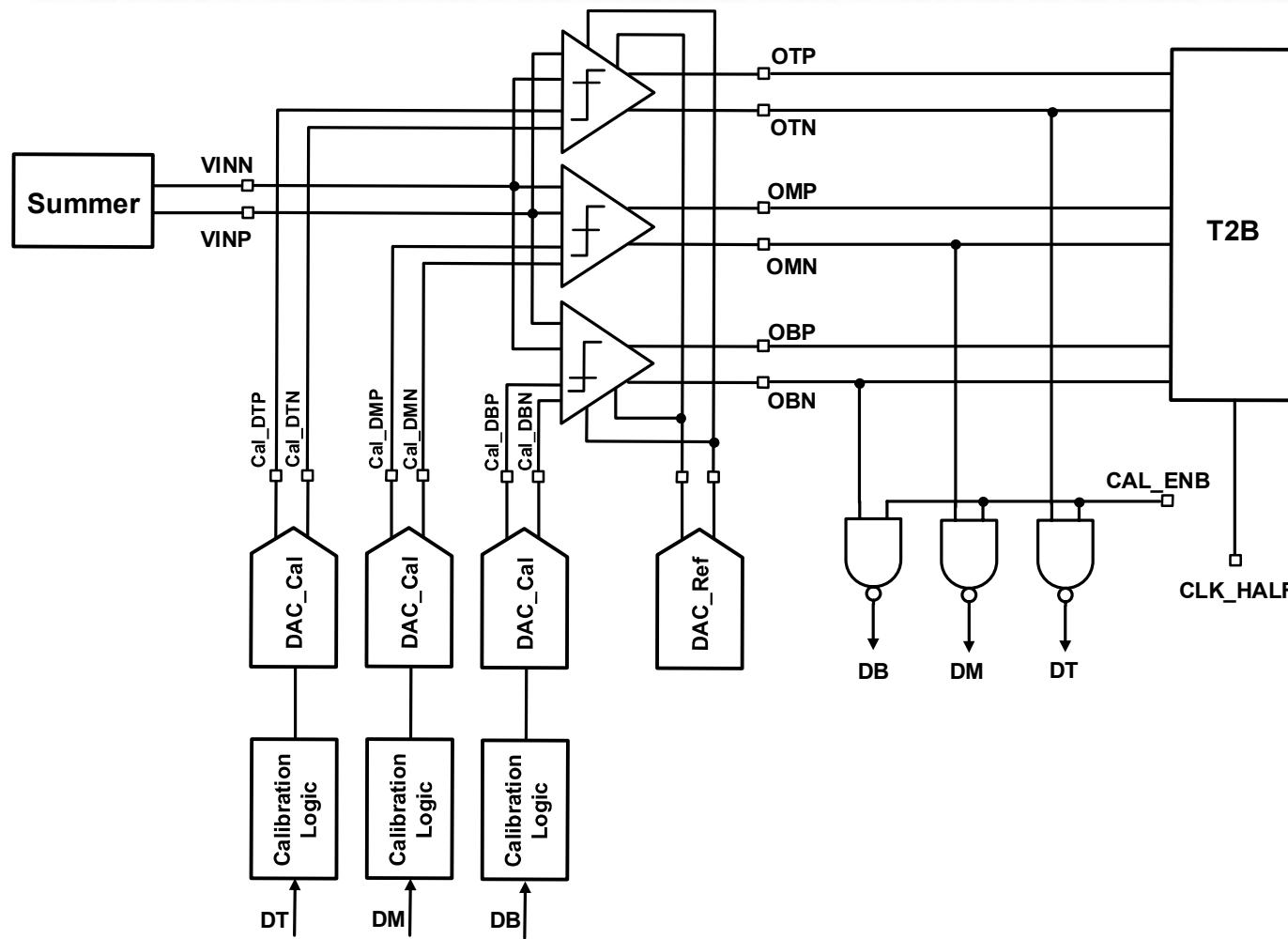
Reference

- [7] S. Daneshgar, H. Li, T. Kim and G. Balamurugan, "A 128 Gb/s, 11.2 mW single-ended PAM4 linear TIA with 2.7 μ Arms input noise in 22 nm FinFET CMOS," *IEEE J. Solid-State Circuits*, vol. 57, no. 5, pp. 1397-1408, May 2022.
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- [9] M. Kashani, H. Shakiba and A. Sheikholeslami, "A 0.32pJ/b 90Gbps PAM4 optical receiver front-end with automatic gain control in 12nm CMOS FinFET," in *Proc. IEEE Symp. VLSI Technol. Circuits (VLSI Technol. Circuits)*, June 2023, pp. 1-2.
- [4] M. Parvizi et al., "A 112-Gb/s, -10 dBm sensitivity, +5 dBm overload, and SiPh-based receiver frontend in 22-nm FDSOI," *IEEE Solid-State Circuits Lett.*, vol. 7, pp. 263-266, 2024.
- [5] S. Ma et al., "A 85-Gb/s PAM-4 TIA With 2.2-mApp Maximum Linear Input Current in 28-nm CMOS," *IEEE Solid-State Circuits Lett.*, vol. 7, pp. 50-53, 2024.

Thank you

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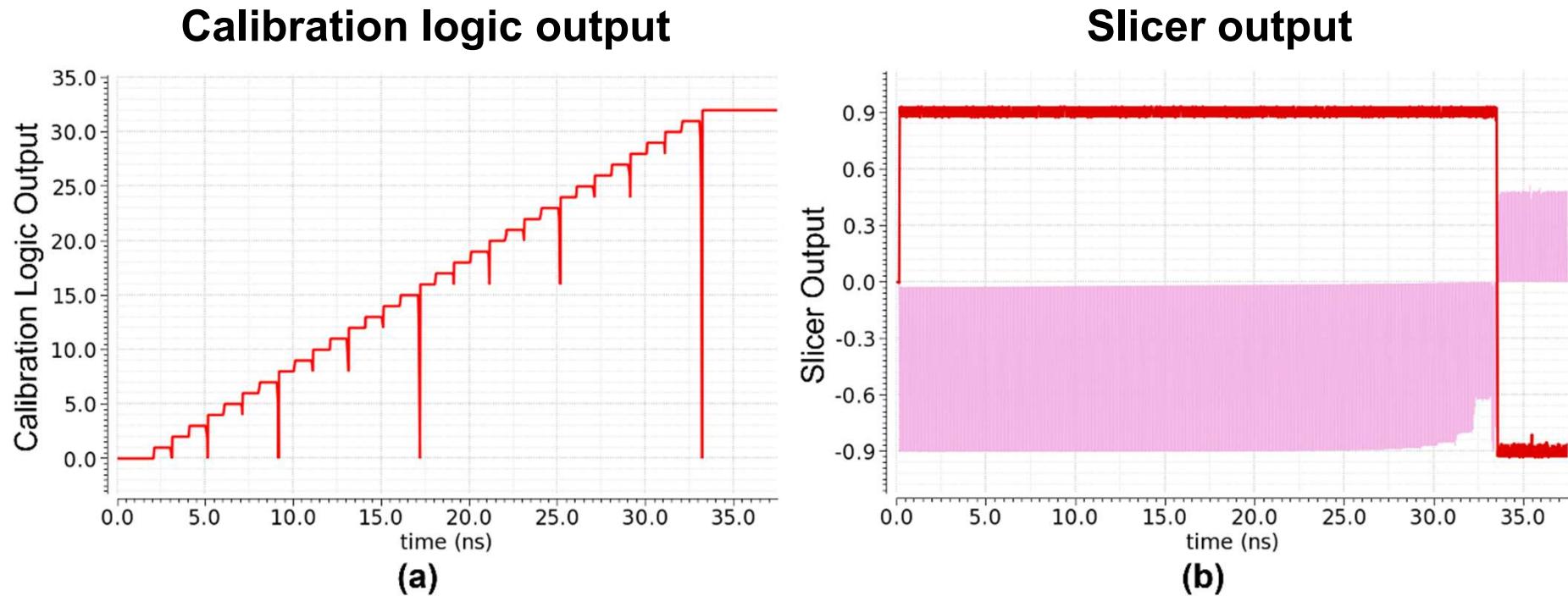
Back-up: Calibration Logic



Slicers with calibration circuits

- Calibration logic
- 6-bit calibration DACs, **DAC_Cal**

Back-up: Calibration Logic



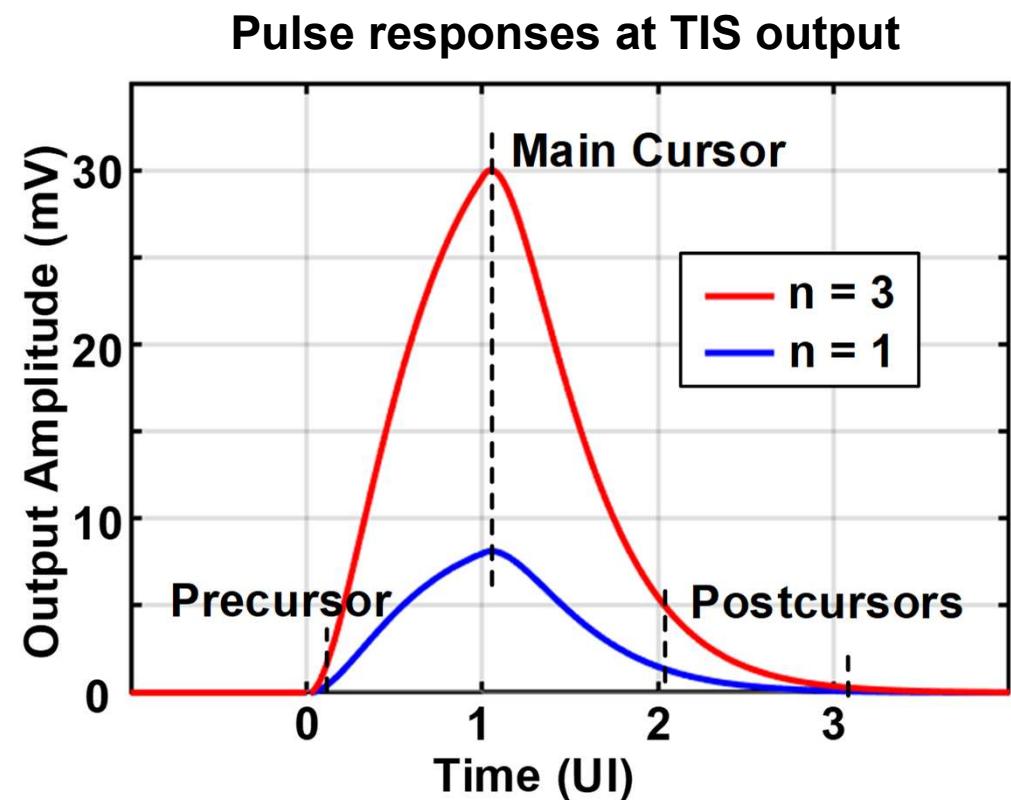
- If the comparator does not generate ‘0’ within 8 clock cycles, calibration logic output increases by 1 and DAC_cal increases by 1 MSB
- The process continues until a transition from ‘1’ to ‘0’ happens at slicer output and the calibration ends

Back-up: V_{ISI} Calculation

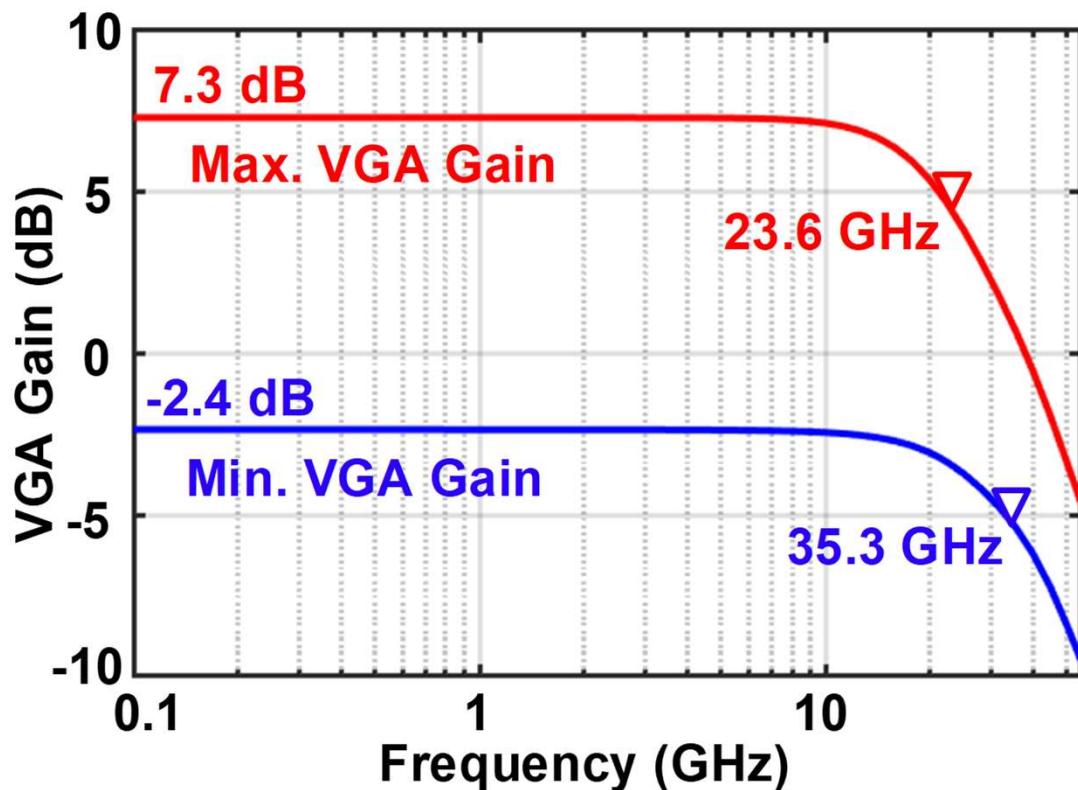
- Worst eye opening V_{ISI} for PAM-4 is calculated from

$$V_{ISI} = |V_0| - 3 \sum_{i \neq 0} |V_i|$$

- V_0 is the main cursor
- V_i is the i_{th} pre/post cursors

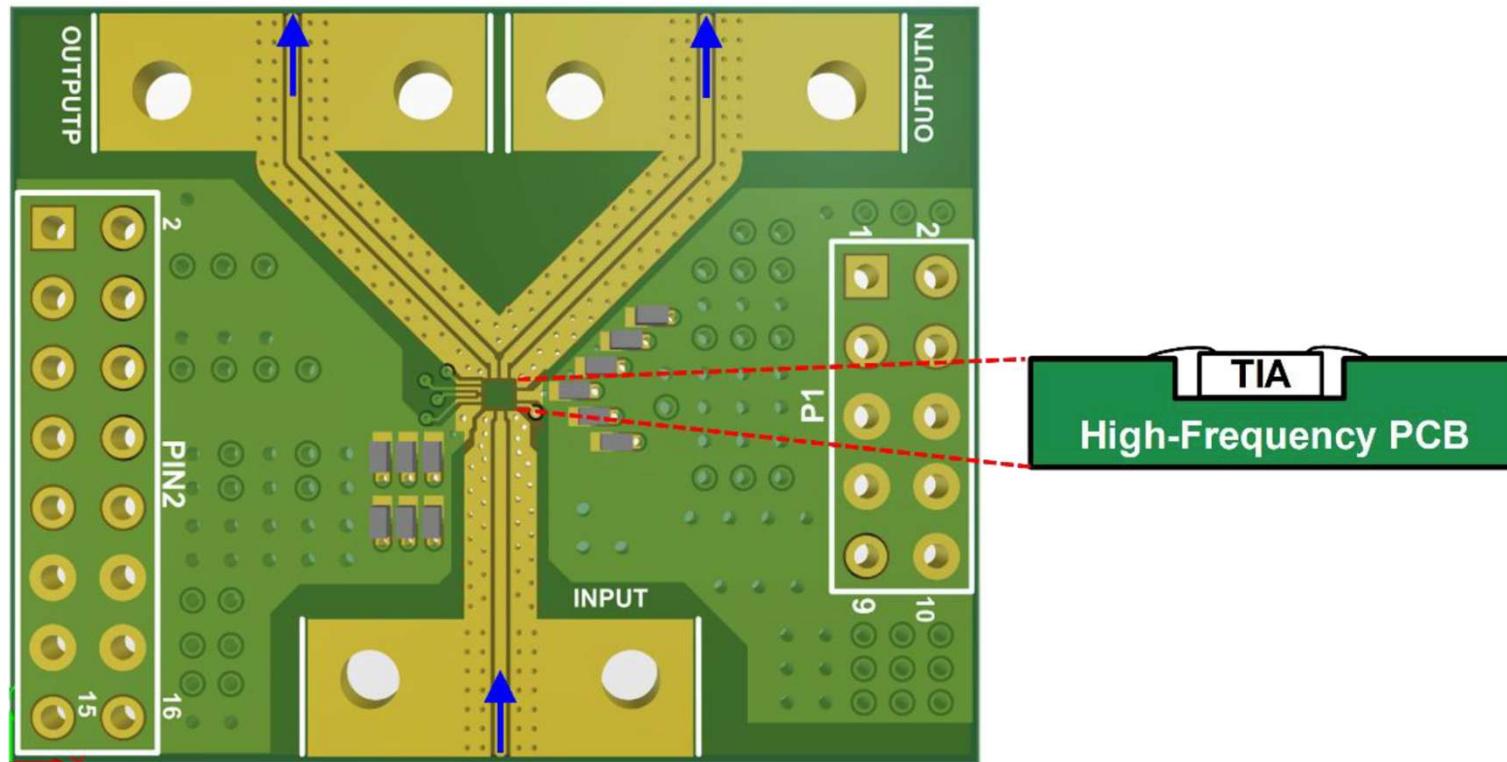


Back-up: Response of Proposed VGA in 100-Gb/s TIA



- 7.3 dB with 23.6 GHz BW
- -2.4 dB with 35.3 dB
- 9.7 dB dynamic range, 11.7 GHz BW variation

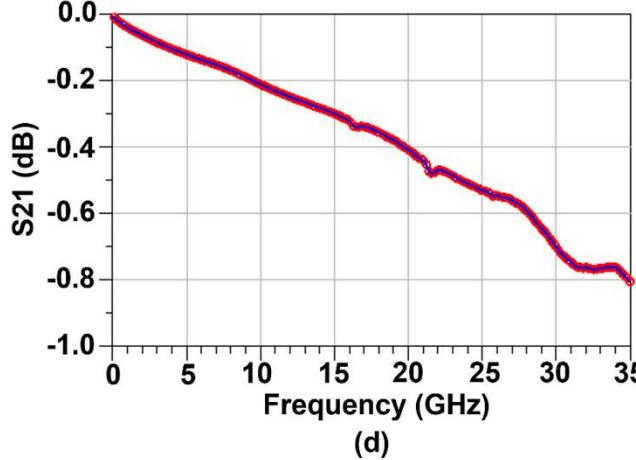
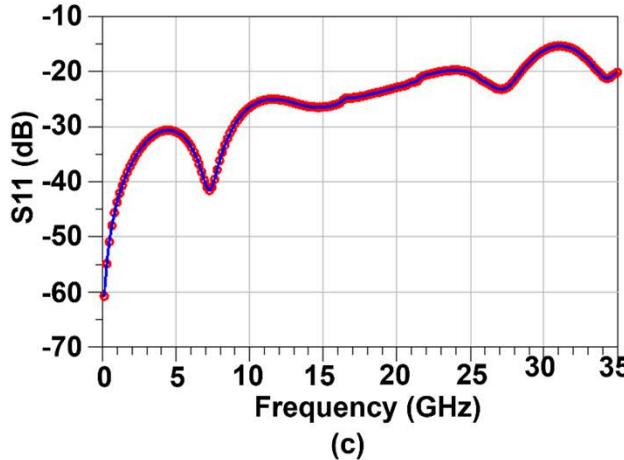
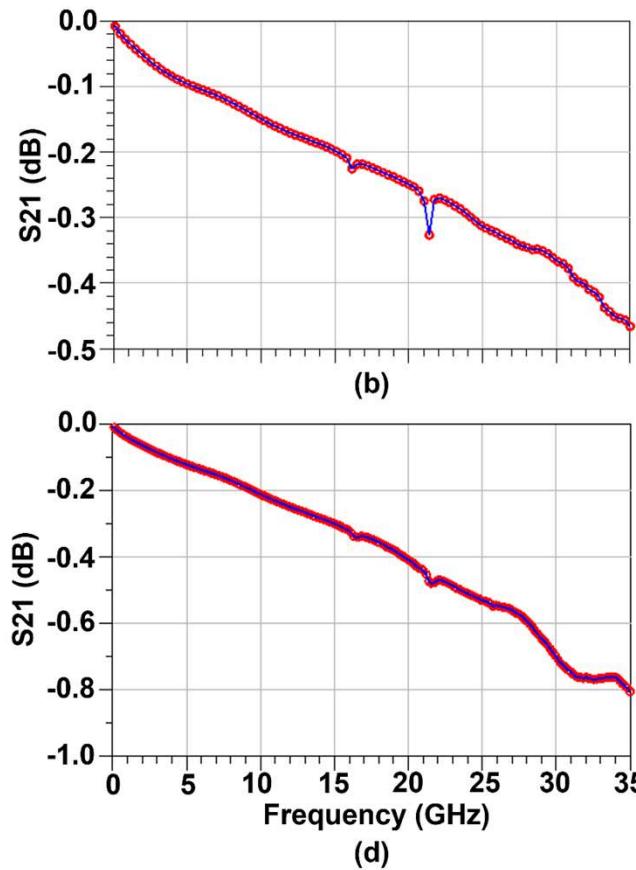
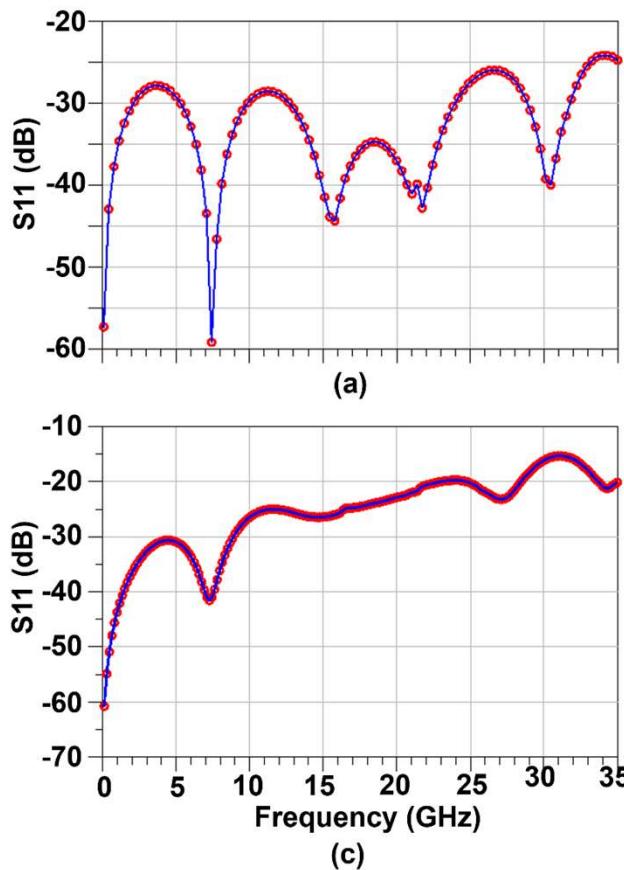
Back-up: High-Frequency PCB Design



- 10-mil RO4350B material for laminates
- PCB is trenched to accommodate the TIA die, reducing the length of bond wires

Back-up: High-Frequency PCB Design

Simulated S parameters of PCB traces



Input trace:

- S₁₁ < -20 dB up to 35 GHz
- S₂₁ > -0.4 dB at 25 GHz

Output trace:

- S₁₁ < -10 dB up to 35 GHz
- S₂₁ > -0.6 dB at 25 GHz